



FCC TAS validation – Part 2: Tests under dynamic transmit power scenarios

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Equipment : Phone
Model Name : GXQ96
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Mountain View, California, 94043 USA
Standard : FCC 47 CFR Part 2 (2.1093)

The product was received on Aug. 28, 2024 and testing was started from Sep. 03, 2024 and completed on Sep. 19, 2024. We, SPORTON INTERNATIONAL INC., would like to declare that the tested sample provide by manufacturer and the test data has been evaluated in accordance with the test procedures given in 47 CFR Part 2.1093 and FCC KDB and has been pass the FCC requirement.

The test results in this report apply exclusively to the tested model / sample. Without written approval of SPORTON INTERNATIONAL INC. EMC & Wireless Communications Laboratory, the test report shall not be reproduced except in full.

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History of this test report

Report No.	Version	Description	Issued Date
FA451606C	01	Initial issue of report	Sep. 25, 2024

1. Introduction

This purpose of this Part 2 report is to demonstrate that the DUT complies with FCC RF exposure compliance requirement under varying Tx power transmission scenarios, thus validating the Samsung S.LSI TAS algorithm feature for FCC equipment authorization of the handset.

The values of P_{limit} used in this report per scenario are determined in Part 0 report.

2. Tx Varying Transmission Test Cases and Test Proposal

The following scenarios are covered in this report to demonstrate compliance with FCC RF exposure in Tx varying transmission conditions.

1. During a time-varying Tx power transmission – to prove that TAS feature accounts for Tx power variations in time accurately.
2. During a call disconnect and re-establish scenario – to prove that the TAS feature accounts for history of Tx power from past accurately
3. During a technology/band handover – to prove that TAS feature accounts for history across transitions in band/technology
4. During operating state change – to prove that TAS feature functions correctly to meet compliance limits across operate state changes
5. During time averaging window change – to prove that TAS feature properly handles the change from one time averaging window to another as specified by FCC, and meets the normalized FCC limit of 1.0 at all time

As described in Part 0, the RF exposure is proportional to the Tx power for sub-6. Thus, we rely on conducted power measurements (sub-6) in each dynamic case to demonstrate that overall RF exposure is within the FCC limit.

The overall procedure for validating the test is summarized below:

1. Measure conducted power over time, denoted as $TxPower(t)$, with time index t for each radio
2. Convert measured powers to RF exposure values using linear relationship shown below. In below expression, $P_{limit,sub-6}$ would be the measured power at which FR1 technology meets measured SAR level of SAR_{design_target} as described in Part 0.

$$SAR(t) = \frac{TxPower(t)}{P_{limit,sub-6}} * SAR_{design\_target} \quad (2.1.1)$$

3. Compute the average RF exposure over the most recent measurement duration which are denoted as $TSAR$ for sub6 . These durations are as specified by FCC. This measurement duration interval is then given by $[t - TSAR, t]$ for sub-6.
4. Divide the RF exposure by corresponding FCC limit and ensure the sum denoted as TER (total exposure ratio) is less than 1 for all. The following equation describes the calculation of TER and its target constraint. $LSAR$ is the number of fixed, mobile or portable RF sources using SAR-based formula, the expressions below is general considering a number radios in general denoted by $LSAR$.

$$\sum_{LSAR=0}^{LSAR-1} \frac{SAR_{avr, LSAR}}{FCC SAR} \leq 1 \quad (2.1.3)$$

3. SAR Time Averaging Validation Test Procedures

Test plan and test procedure for validating Samsung SLSI TAS feature for sub-6 scenarios

3.1 Test sequence determination for validation

Two sequences for time varying Tx power are pre-defined as given below for sub-6 case.

1. Test Sequence A is generated with two power levels. One is maximum power level P_{max} and the other is lower power level. The lower power level is defined as 3dB lower value than maximum power level. At first, maximum power level is applied for 80 seconds. After this, lower power level is used until this test is finished.
2. Test Sequence B is generated at multiple power levels that are specified in the Appendix as a function of P_{max} and P_{limit} .

3.2 Test configuration selection criteria for validating TAS

This section provides general guidance for selecting test cases in TAS feature validation.

3.2.1 Test configuration selection for time-varying Tx power transmission

The Samsung S.LSI TAS algorithm is independent of band, modes or channel of any technology. Hence, we can validate using one or two combinations of band/mode/channel per technology. The criteria for selecting these would be based on the relative value of P_{limit} and P_{max} as determined in Part 0. Essentially, we need to pick this combination such that P_{limit} is less than P_{max} so that the TAS algorithm will enforce power restriction. Two bands can be selected from Part 0 with different values of P_{limit} -select one corresponding to lowest P_{limit} and another being highest but still less than P_{max} .

3.2.2 Test configuration selection for change in call

The criteria to select the technology/band for transition between call setup and call drop is to choose the one with least P_{limit} among all bands in Part 0. The test is performed with DUT requested power at P_{max} so that the Samsung S.LSI TAS feature enforces power restriction for longest duration. The call change is performed when the DUT is operating with restricted power. One such test is sufficient since behavior is not dependent on band/technology.

3.2.3 Test configuration for change in technology/band/window

FCC specifies different measurement durations for time averaging based on operating frequency. The change of operating frequency can result in change of time window for averaging, for e.g. change from 100s averaging for frequency below 3GHz to 60s averaging for frequency above 3-6 GHz, The criteria for selecting test case to demonstrate compliance across time window change is to pick a technology/band corresponding to each time window from Part 0 such that Plimit is less than Pmax.

3.3 Test procedures for conducted power measurements

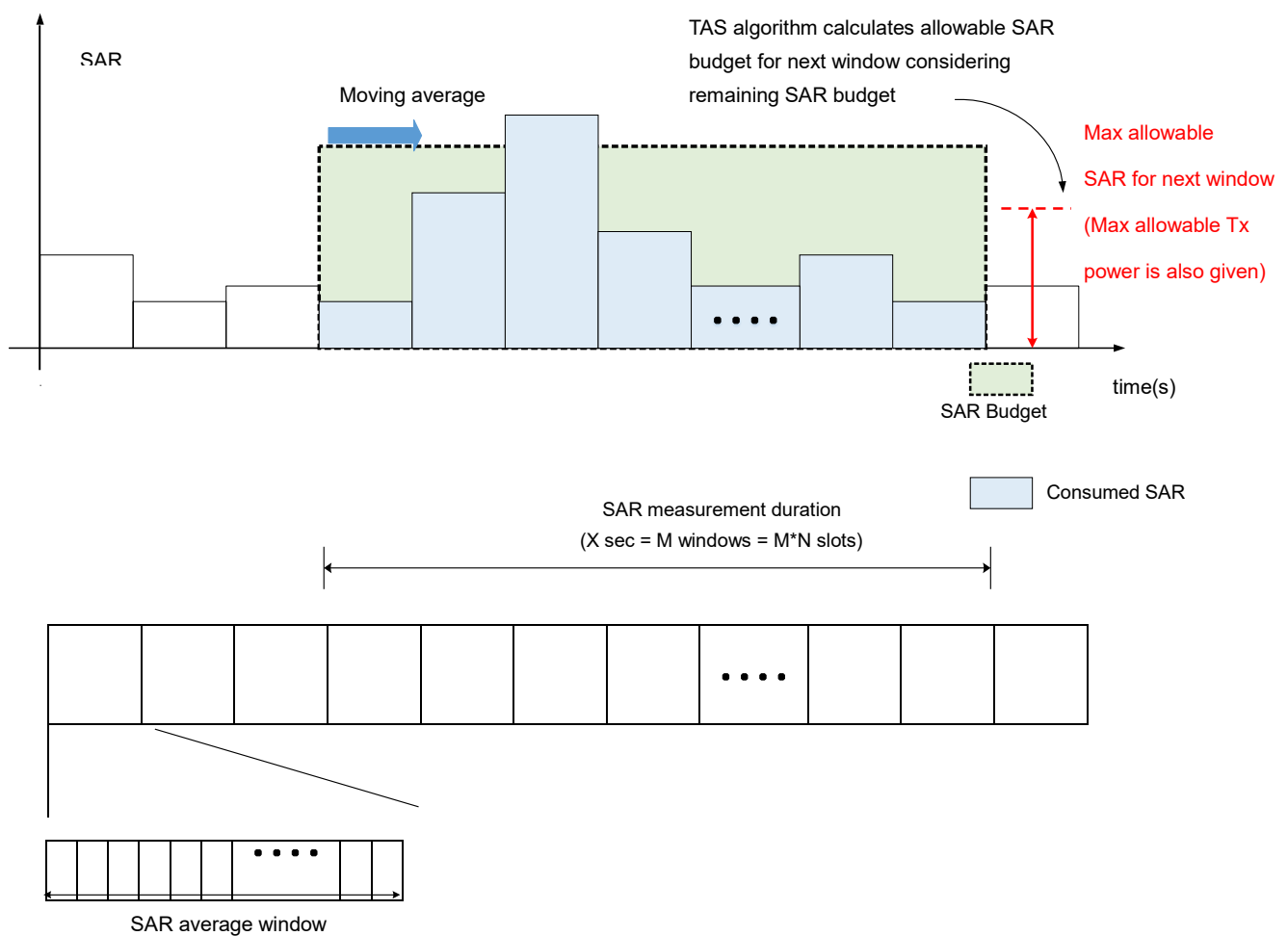
This section provides general conducted power measurement procedures to perform compliance test under dynamic scenarios described in Section 2.

3.3.1 Time-varying Tx power transmission scenario

This test is performed with two pre-defined test sequences as described in Section 3.1 for all technologies operating on sub-6GHz applying to both UMTS, LTE and NR as selected in Section 3.2.1. The purpose of the test is to demonstrate the maximum power limiting enforcement and that the time-averaged SAR does not exceed the FCC limit at all times.

3.3.1.1 Test procedure

1. Using the Pmax and Plimit obtained in Part 0/1, generate the test sequence of power levels for each selected technology/band. Both test sequences A and B are generated. Maximum power can be changed according to DUT test results.
2. Establish the connection of the DUT to the call box in the selected RAT, with the call box requesting the DUT Tx power to be according to the sequence determined in Step 1. An initial value of Tx power will be set to 0dBm for 100s before the desired test sequence starts to help with post-processing of the time-average value with the very first value in the sequence. This is illustrated in the figure below



Average SAR value in a slot can be calculated from average Tx power in the slot
(Assume that SAR vs Tx power relation is obtained from real measurement)

Figure 3.3-1 SAR measurement from Tx power using block-wise processing

3. Release connection.
4. After the completion of the test, prepare one plot with the following information:
 - a. Instantaneous Tx power versus time measured in Step 2
 - b. Requested Tx power versus time used in Step 2
 - c. Time-averaged power over 100s using instantaneous values from Step 2
 - d. Power level Plimit which is determined as meeting SAR target in Part 0/1
5. Make a second plot containing the following information:
 - a. Computed time-averaged 1gSAR versus time determined in Step 2
 - b. FCC 1gSAR limit of 1.6W/kg

The pass condition is to demonstrate time-averaged 1gSAR versus time shown in Step 5 value versus time does not exceed the FCC limit of 1.6 W/kg throughout the test duration. We would also demonstrate that time-averaged power does not exceed the Plimit at any time in the plot in Step 4.

3.3.2 Change in call scenario

This test is to demonstrate that Samsung S.LSI TAS feature correctly accounts for past Tx powers during time- averaging when a new call is established. The call change has to be carried out when the power limit enforcement is ongoing.

3.3.2.1 Test procedure

1. Establish radio connection of DUT with call box e.g. using LTE technology
2. Configure call box to set DUT Tx power to a low value of -10dBm for 100s.
3. Configure call box to send "ALL UP" power control commands and continue LTE transmission from DUT so that maximum power of Pmax is achieved.
4. After 60s of transmission at Pmax power level, release the call from call box.
5. After 10s, re-establish the LTE connection from call box to DUT and repeat sending "ALL UP" power control command to bring the Tx power to Pmax level again.
6. Continue LTE transmission at Pmax level for another 110s.
7. Release LTE connection.
8. After the completion of the test, prepare one plot with the following information (a) Instantaneous Tx power versus time (b) Requested Tx power versus time (c) Time-averaged power over 100s using instantaneous values and (d) Power level Plimit which is determined as meeting SAR target
9. Make a second plot containing the following information (a) Computed time-averaged 1gSAR versus time and (b) FCC 1gSAR limit of 1.6W/kg

Pass condition is to demonstrate time-averaged 1gSAR value versus time does not exceed the FCC limit of 1.6 W/kg throughout the test duration. It is required to check if SAR calculation is accounting for call drop and connection. Current TAS algorithm software makes the UE estimate the exact amount of Tx power and average SAR even during call drop and call re-establishment event. The UE stores time information when it goes into a sleep mode and wake-up to calculate Tx power on / off duration.

3.3.3 Change in technology/band/window

This test is to demonstrate that Samsung S.SLSI TAS feature can properly handle change of technology/band and consequently time window as necessary during handover scenarios. Since both Plimit and window duration can change across bands, we have to use separate equations below for converting Tx power to SAR as well as apply a combined SAR exposure criterion as shown below.

$$SAR\ 1\ (t) = \frac{TxPower(t)}{Plimit,sub6} * SAR\_design\_target \quad (3.3.1)$$

$$SAR\ 2\ (t) = \frac{TxPower(t)}{Plimit,sub6} * SAR\_design\_target \quad (3.3.2)$$

where $Plimit,1,FR1$ would correspond to measured power at which first technology/band meets measured SAR level of $SAR\_design\_target1$ as described in Part 0 and Part 1 with time-averaging duration of $T1,SAR$. Similarly, $Plimit,FR2$ would be the measured EIRP at which FR2 technology meets measured PD level of PD_design_target as described in Part 0. Similarly, the quantities $Plimit,2,FR1$, $SAR\_design\_target2$, $T2,SAR$ are defined for the second technology/band.

3.3.4 Change in Power Index

This test is to demonstrate that Samsung S.LSI TAS feature can properly handle change of RSI resulting from different SAR index state detected by host platform software. It involves changing the Plimit value during the test for the same technology to emulate power index change.

3.3.5 Test configuration for SAR exposure switching

The criteria for selecting test case is to pick an LTE band and a NR band with Plimit lower than Pmax in each case. The test is performed with both RATs connected in an EN-DC scenario. In the first portion of the test, DUT is requested to transmit at maximum power for NR and minimum power for LTE. In the second portion of the test, DUT is requested to transmit at maximum power for both NR and LTE. In the final portion of the test, DUT is requested to transmit at minimum power for NR and maximum power for LTE.

3.3.6 Test procedure for handover between two TAS RATs

1. Establish radio connection of DUT with call box e.g. using NR band
2. Configure call box to set DUT Tx power to a low value of 0dBm for 110s.
3. Configure call box to send "ALL UP" power control commands and continue NR transmission from DUT so that maximum power of Pmax is achieved. Continue transmission at the maximum power for 120s.
4. Change RAT from NR to LTE and configure call box to send "ALL UP" power control commands in LTE
5. Continue call in LTE at maximum power for 400s

3.3.7 Test configuration for Uplink CA

The criteria for selecting this test case is to demonstrate the compliance of the TAS algorithm when an LTE or FR1 transmission is done over multiple CC. This test shows that the TAS algorithm compliance is independent on the Transmission scenarios (single CC or CA), select any one technology that the EUT supports to demonstrate compliance.

4. Spatial TAS

In legacy TAS algorithm (V2.3), it was assumed that all antennas are correlated regardless of their direction of transmission in space. Thus, the main concept was to split the SAR/TER on the transmitting RATs even they are transmitting on different antennas. Such approach is considered as a worst case scenario in terms of transmitting power. Thus, to enhance the performance of the transmission power of RATs, we should consider the spatial properties of each antenna and the correlations between the antennas transmissions. The TAS algorithm from the latest Samsung submission document revision v2.7 is implemented.

For example, consider a DUT with two antennas one at the top and one at the bottom and each are transmitting in two different direction with no common area affected by both. For such DUT architecture, if each antenna utilize the full SAR compliance while transmitting simultaneously, then the power transmission is still under compliance since no area is affected by both transmissions and thus no area will have SAR above SAR compliance.

For a DUT with N antennas, a spatial correlation matrix (R) can be constructed to map the correlation between each two antennas when they transmit simultaneously. Thus this correlation matrix is given as

$$R = \begin{bmatrix} r_{11} & r_{12} & \dots & r_{1N} \\ r_{21} & r_{22} & \dots & r_{2N} \\ \vdots & \vdots & \ddots & \vdots \\ r_{N1} & r_{N2} & \dots & r_{NN} \end{bmatrix}$$

And it has the following characteristics

- a) r_{ij} is the correlation between antenna i and antenna j
- b) The value of r_{ij} is either 0 or 1, where 1 means fully correlated and 0 means fully uncorrelated.
- c) r_{ii} is the self-correlation of each antenna and it is always 1

For ENDC operation, the value of the correlation coefficients (r_{ij}) between the two transmitting antennas (i,j) will determine the splitting ratios between the two operating RATs as follow

- a) If $r_{ij} = 0$ then each antenna will transmit with full SAR compliance
- b) If $r_{ij} = 1$ then the full SAR compliance will be split among both antennas with ration a:b, where $a + b = 1$

Since the R matrix entries depends on the antenna distribution of each DUT, then our spatial TAS algorithm is implemented to operate with any R matrix (antenna distribution agnostic).

The values of the R matrix entries should be determined by the OEM based on the DUT used. One way to determine the values of the R matrix entries is to use the SPLSR test mentioned in FCC KDB 447498 D01, section 4.3.2.

The SPLSR test is done between each pair of antennas as follow

- i. Measure the SAR peak location for each antenna (x_i, y_i, z_i) and (x_j, y_j, z_j)
- ii. Calculate $\Gamma_{ij} = \frac{(SAR_{i,max} + SAR_{j,max})^{1.5}}{D}$, where $SAR_{i,max} = SAR_{j,max} = SAR_{comp}$ and $D = \sqrt{(x_i - x_j)^2 + (y_i - y_j)^2 + (z_i - z_j)^2}$
- iii. Check if the value of $\Gamma_{ij} \leq 0.04$ for 1g and 0.1 for 10g then these two antennas are considered fully uncorrelated and we can set $r_{ij} = 0$. Otherwise, a Volumetric SAR evaluation can be done to check the non-correlation of both antennas and if not set $r_{ij} = 1$
- iv. If volumetric SAR cannot meet FCC SAR compliance requirements, set $r_{ij} = 1$.

NOTE: The antennas corresponding to the selected RSIs or change in technology/band/window should be in the rij=1 if EUT is configured Spatial TAS algorithm.

5. Test Configurations

5.1 WWAN (sub-6) transmission

- 1 The Plimit values correspond to SAR_design_target.
- 2 GSM doesn't support time average feature of dynamic power varying, the power will be fixed at the static reduce power level at different exposure conditions for RF exposure compliance. For the GSM Plimit power levels in the table correspond to the burst average power levels which don't account for TX duty cycle.
- 3 UMTS, LTE and 5GNR TDD: Plimit power levels in the table correspond to the time-averaged power levels which accounts for TX duty cycle.
- 4 Maximum target power, Pmax, is configured in NV settings in EUT to limit maximum transmitting power. This power is converted into peak power in NV settings for TDD schemes.

Table 6.1.1: P_{limit} for supported technologies and bands (P_{limit} corresponding to SAR design target)

Wireless technology/ band (No Accounting duty cycle)	Antenna	Duty cycle	Max Power Condition	Head		Hotspot	Body-worn/Extremity		P Max Burst average power (dBm)
				Standalone	Simultaneous	Simultaneous	Standalone	Simultaneous	
			Index 1	Index 2	Index 3	Index 4	Index 5	Index 6	
			P limit						
			Burst average power (dBm)						
GSM850 GSM/GPRS 1TX	0	12.50%	32.50	37.50	33.80	34.20	35.30	34.20	32.50
GSM850 GPRS 2TX	0	25.00%	31.50	34.50	30.80	31.20	32.30	31.20	31.50
GSM850 GPRS 3TX	0	37.50%	30.50	32.70	29.00	29.40	30.50	29.40	30.50
GSM850 GPRS 4TX	0	50.00%	29.00	31.50	27.80	28.20	29.30	28.20	29.00
GSM850 EDGE 1TX	0	12.50%	27.00	37.50	33.80	34.20	35.30	34.20	27.00
GSM850 EDGE 2TX	0	25.00%	26.50	34.50	30.80	31.20	32.30	31.20	26.50
GSM850 EDGE 3TX	0	37.50%	26.50	32.70	29.00	29.40	30.50	29.40	26.50
GSM850 EDGE 4TX	0	50.00%	24.50	31.50	27.80	28.20	29.30	28.20	24.50
GSM850 GSM/GPRS 1TX	1	12.50%	32.00	30.00	27.90	31.20	34.30	31.20	32.00
GSM850 GPRS 2TX	1	25.00%	31.50	27.00	24.90	28.20	31.30	28.20	31.50
GSM850 GPRS 3TX	1	37.50%	29.50	25.20	23.10	26.40	29.50	26.40	29.50
GSM850 GPRS 4TX	1	50.00%	27.00	24.00	21.90	25.20	28.30	25.20	27.00
GSM850 EDGE 1TX	1	12.50%	26.50	30.00	27.90	31.20	34.30	31.20	26.50
GSM850 EDGE 2TX	1	25.00%	26.00	27.00	24.90	28.20	31.30	28.20	26.00
GSM850 EDGE 3TX	1	37.50%	26.00	25.20	23.10	26.40	29.50	26.40	26.00
GSM850 EDGE 4TX	1	50.00%	23.00	24.00	21.90	25.20	28.30	25.20	23.00
GSM1900 GSM/GPRS 1TX	2	12.50%	29.50	36.10	35.40	30.80	30.80	30.80	29.50
GSM1900 GPRS 2TX	2	25.00%	28.50	33.10	32.40	27.80	27.80	27.80	28.50
GSM1900 GPRS 3TX	2	37.50%	28.00	31.30	30.60	26.00	26.00	26.00	28.00
GSM1900 GPRS 4TX	2	50.00%	27.00	30.10	29.40	24.80	24.80	24.80	27.00
GSM1900 EDGE 1TX	2	12.50%	25.00	36.10	35.40	30.80	30.80	30.80	25.00
GSM1900 EDGE 2TX	2	25.00%	24.00	33.10	32.40	27.80	27.80	27.80	24.00
GSM1900 EDGE 3TX	2	37.50%	24.00	31.30	30.60	26.00	26.00	26.00	24.00
GSM1900 EDGE 4TX	2	50.00%	23.00	30.10	29.40	24.80	24.80	24.80	23.00
GSM1900 GSM/GPRS 1TX	0	12.50%	29.00	35.70	35.00	30.50	32.30	30.50	29.00
GSM1900 GPRS 2TX	0	25.00%	28.50	32.70	32.00	27.50	29.30	27.50	28.50
GSM1900 GPRS 3TX	0	37.50%	27.50	30.90	30.20	25.70	27.50	25.70	27.50
GSM1900 GPRS 4TX	0	50.00%	26.50	29.70	29.00	24.50	26.30	24.50	26.50
GSM1900 EDGE 1TX	0	12.50%	25.00	35.70	35.00	30.50	32.30	30.50	25.00
GSM1900 EDGE 2TX	0	25.00%	23.50	32.70	32.00	27.50	29.30	27.50	23.50
GSM1900 EDGE 3TX	0	37.50%	23.50	30.90	30.20	25.70	27.50	25.70	23.50
GSM1900 EDGE 4TX	0	50.00%	22.50	29.70	29.00	24.50	26.30	24.50	22.50



Table 6.1.2: P_{limit} for supported technologies and bands (P_{limit} corresponding to SAR design target)

Wireless technology/ band (Accounting duty cycle)	Antenna	Duty cycle	Max Power Condition	Head		Hotspot	Body-worn/Extremity		P Max Time- average power (dBm)
				Standalone	Simultaneous	Simultaneous	Standalone	Simultaneous	
			Index 1	Index 2	Index 3	Index 4	Index 5	Index 6	
			P limit						
			Time-average power (dBm)						
WCDMA B2	2	100.00%	24.70	25.70	23.50	21.10	21.10	21.10	24.70
WCDMA B2	0	100.00%	24.20	25.80	23.20	20.90	23.00	20.90	24.20
WCDMA B4	2	100.00%	24.70	26.70	24.50	21.30	21.30	21.30	24.70
WCDMA B4	0	100.00%	24.20	27.20	26.50	22.60	24.10	22.60	24.20
WCDMA B5	0	100.00%	24.70	28.30	24.00	24.50	25.90	24.50	24.70
WCDMA B5	1	100.00%	24.20	20.60	18.50	21.50	25.00	21.50	24.20
LTE Band 2	1	100.00%	24.70	15.30	13.50	17.70	20.50	17.70	24.70
LTE Band 2	5	100.00%	24.20	17.10	15.90	20.00	21.70	20.00	24.20
LTE Band 7	2	100.00%	24.70	24.70	22.70	20.30	20.60	20.60	24.70
LTE Band 7	0	100.00%	24.20	26.30	23.90	20.00	22.60	20.00	24.20
LTE Band 12/B17	0	100.00%	24.70	30.80	30.10	24.70	25.40	24.70	24.70
LTE Band 12/B17	1	100.00%	24.20	21.40	20.00	24.10	27.50	24.10	24.20
LTE Band 13	0	100.00%	24.70	29.30	28.60	24.20	26.20	24.30	24.70
LTE Band 13	1	100.00%	24.70	21.40	19.60	22.20	25.70	22.20	24.70
LTE Band 14	0	100.00%	24.70	29.00	24.60	24.10	25.90	24.60	24.70
LTE Band 14	1	100.00%	24.70	21.10	19.70	22.40	25.80	22.40	24.70
LTE Band 25/B2	2	100.00%	24.70	27.00	26.30	21.20	21.20	21.20	24.70
LTE Band 25/B2	0	100.00%	24.20	26.80	24.10	21.70	22.40	21.70	24.20
LTE Band 26/B5	0	100.00%	24.70	28.30	24.40	24.50	25.80	25.10	24.70
LTE Band 26/B5	1	100.00%	24.20	20.40	18.30	21.70	25.40	21.70	24.20
LTE Band 30	2	100.00%	24.70	26.40	24.30	20.50	20.50	20.50	24.70
LTE Band 30	0	100.00%	24.20	28.60	27.90	23.60	24.60	23.60	24.20
LTE Band 41/B38 PC3	2	63.30%	22.70	24.10	22.00	20.30	20.70	20.70	22.70
LTE Band 41/B38 PC2	2	43.30%	22.90	24.10	22.00	20.30	20.70	20.70	22.90
LTE Band 41/B38 PC3	0	63.30%	22.20	28.30	27.60	20.60	23.50	20.60	22.20
LTE Band 41/B38 PC2	0	43.30%	22.40	28.30	27.60	20.60	23.50	20.60	22.40
LTE Band 48 PC3	6	63.30%	21.60	25.40	24.70	19.90	19.90	19.90	21.60
LTE Band 48 PC3	2	63.30%	21.50	23.80	23.10	19.10	20.20	20.20	21.50
LTE Band 66/B4	2	100.00%	24.70	27.90	27.20	21.40	21.40	21.40	24.70
LTE Band 66/B4	0	100.00%	24.20	27.50	26.80	22.40	23.70	22.40	24.20
LTE Band 66	1	100.00%	24.70	15.30	14.50	19.30	21.60	19.30	24.70
LTE Band 66	5	100.00%	24.20	18.70	17.50	22.10	22.10	22.10	24.20
LTE Band 71	0	100.00%	24.70	31.10	30.40	26.40	27.10	26.40	24.70
LTE Band 71	1	100.00%	24.20	21.50	19.30	26.60	27.30	26.60	24.20

Table 6.1.3: P_{limit} for supported technologies and bands (P_{limit} corresponding to SAR design target)

Wireless technology/ band (Accounting duty cycle)	Antenna	Duty cycle	Max Power Condition	Head		Hotspot	Body-worn/Extremity		P Max Time- average power (dBm)	
				Standalone	Simultaneous	Simultaneous	Standalone	Simultaneous		
			Index 1	Index 2	Index 3	Index 4	Index 5	Index 6		
			P limit							
			Time-average power (dBm)							
FR1 n7	2	100.00%	24.70	24.40	22.90	20.30	21.00	20.30	24.70	
FR1 n7	0	100.00%	24.20	26.30	23.80	19.60	22.60	19.60	24.20	
FR1 n12	0	100.00%	24.70	29.60	28.90	24.90	25.60	24.90	24.70	
FR1 n12	1	100.00%	24.20	21.10	19.50	27.30	28.00	27.30	24.20	
FR1 n14	0	100.00%	24.70	29.10	24.20	24.30	25.90	24.30	24.70	
FR1 n14	1	100.00%	24.70	21.30	20.10	23.00	26.50	23.00	24.70	
FR1 n25/n2	2	100.00%	24.70	25.40	23.30	21.10	21.10	21.10	24.70	
FR1 n25/n2	0	100.00%	24.20	25.80	23.30	21.60	23.00	21.60	24.20	
FR1 n26/n5	0	100.00%	24.70	29.00	24.50	24.70	25.40	24.70	24.70	
FR1 n26/n5	1	100.00%	24.20	20.50	18.80	22.10	25.60	22.10	24.20	
FR1 n30	2	100.00%	24.70	26.40	24.30	20.00	20.70	20.00	24.70	
FR1 n30	0	100.00%	24.20	28.80	28.10	23.00	24.60	23.00	24.20	
FR1 n41/n38 PC3	2	100.00%	24.70	24.50	22.50	20.60	20.70	20.70	24.70	
FR1 n41 PC2	2	50.00%	23.50	24.50	22.50	20.60	20.70	20.70	23.50	
FR1 n41 PC1.5	2	25.00%	20.50	24.50	22.50	20.60	20.70	20.70	20.50	
FR1 n41/n38 PC3	0	100.00%	24.20	27.40	26.70	20.90	23.40	20.90	24.20	
FR1 n41 PC2	0	50.00%	23.00	27.40	26.70	20.90	23.40	20.90	23.00	
FR1 n41 PC1.5	0	25.00%	20.00	27.40	26.70	20.90	23.40	20.90	20.00	
FR1 n41 PC3	1	100.00%	24.20	14.90	13.60	18.30	21.40	18.30	24.20	
FR1 n41 PC2	1	50.00%	23.00	14.90	13.60	18.30	21.40	18.30	23.00	
FR1 n41 PC1.5	1	25.00%	20.00	14.90	13.60	18.30	21.40	18.30	20.00	
FR1 n41 PC3	5	100.00%	23.70	15.60	14.60	18.70	21.10	18.70	23.70	
FR1 n41 PC2	5	50.00%	22.50	15.60	14.60	18.70	21.10	18.70	22.50	
FR1 n41 PC1.5	5	25.00%	19.50	15.60	14.60	18.70	21.10	18.70	19.50	
FR1 n48 PC3	6	100.00%	23.60	25.90	25.20	19.30	19.30	19.30	23.60	
FR1 n48 PC3	2	100.00%	23.50	24.80	22.10	18.40	19.90	19.90	23.50	
FR1 n48 PC3	1	100.00%	23.60	15.20	13.10	20.20	20.20	20.20	23.60	
FR1 n48 PC3	5	100.00%	23.50	14.90	14.20	19.60	21.60	19.60	23.50	
FR1 n66	2	100.00%	24.70	26.80	26.10	21.70	21.70	21.70	24.70	
FR1 n66	0	100.00%	24.20	26.70	26.00	21.70	24.00	21.70	24.20	
FR1 n70	2	100.00%	24.70	25.30	24.60	22.10	22.10	22.10	24.70	
FR1 n70	0	100.00%	24.20	28.30	27.60	20.40	23.50	20.40	24.20	
FR1 n71	0	100.00%	24.70	30.90	30.20	25.80	26.50	25.80	24.70	
FR1 n71	1	100.00%	24.20	22.30	20.70	26.80	27.50	26.80	24.20	
FR1 n77/n78 PC3	6	100.00%	24.70	26.20	23.30	19.80	19.80	19.80	24.70	
FR1 n77/n78 PC2	6	50.00%	23.20	26.20	23.30	19.80	19.80	19.80	23.20	
FR1 n77/n78 PC1.5	6	25.00%	20.20	26.20	23.30	19.80	19.80	19.80	20.20	
FR1 n77/n78 PC3	2	100.00%	24.20	24.10	22.00	18.50	20.00	20.00	24.20	
FR1 n77/n78 PC2	2	50.00%	22.70	24.10	22.00	18.50	20.00	20.00	22.70	
FR1 n77/n78 PC1.5	2	25.00%	19.70	24.10	22.00	18.50	20.00	20.00	19.70	
FR1 n77/n78 PC3	1	100.00%	24.70	14.50	12.60	18.60	20.60	18.60	24.70	
FR1 n77/n78 PC2	1	50.00%	23.00	14.50	12.60	18.60	20.60	18.60	23.00	
FR1 n77/n78 PC1.5	1	25.00%	20.00	14.50	12.60	18.60	20.60	18.60	20.00	
FR1 n77/n78 PC3	5	100.00%	24.20	14.60	13.90	20.70	21.90	20.70	24.20	
FR1 n77/n78 PC2	5	50.00%	22.50	14.60	13.90	20.70	21.90	20.70	22.50	
FR1 n77/n78 PC1.5	5	25.00%	19.50	14.60	13.90	20.70	21.90	20.70	19.50	

5.2 Test case list for sub-6GHz transmissions

To validate TAS algorithm in various sub-6GHz conditions, the chosen TC (Test Case) list is defined as in Table 6.2.1.

Table 6.2.1 Sub-6GHz TAS validation test case list

No.	Test Scenario	Test case	Test configuration
1	Time-varying Tx power transmission	LTE_Time_Varying_Tx_Power_Case_1	WCDMA B2
2		LTE_Time_Varying_Tx_Power_Case_1	WCDMA B5
3		LTE_Time_Varying_Tx_Power_Case_1	LTE B48 pc3
4		LTE_Time_Varying_Tx_Power_Case_1	LTE B2
5		SA_FR1_Time_Varying_Tx_Power_Case_1	n30 (SA Mode)
6		SA_FR1_Time_Varying_Tx_Power_Case_1	n77/n78 pc3 (SA Mode)
7	Time-varying Tx power transmission	LTE_Time_Varying_Tx_Power_Case_2	WCDMA B2
8		LTE_Time_Varying_Tx_Power_Case_2	WCDMA B5
9		LTE_Time_Varying_Tx_Power_Case_2	LTE B48 pc3
10		LTE_Time_Varying_Tx_Power_Case_2	LTE B2
11		SA_FR1_Time_Varying_Tx_Power_Case_2	n30 (SA Mode)
12		SA_FR1_Time_Varying_Tx_Power_Case_2	n77/n78 pc3 (SA Mode)
13	Change in power index	SA_FR1_RF_SAR_Index_Change	n77/n78 pc3 (SA Mode) index 3 to Index 4
14	Antenna switch/ Time Window change case 1 60s-100s-60s	LTE_Averaging_Time_Window_Change 1	LTE B7 , LTE B48 pc3
15	Antenna switch/ Time Window change case 2 100s-60s-100s	LTE_Averaging_Time_Window_Change 2	LTE B48 pc3 , LTE B7
16	Drop call	Call_Disconnect_Reestablishment	LTE B2
17	SAR exposure switch	NSA_FR1_Dominant_Power_Switching	LTE B7 , n77/n78 pc3 (NSA Mode)
18	Re-selection in call	NR_TO_LTE_IRAT_HO	n77/n78 pc3 (SA Mode) to LTE B7
19	UL CA	-	LTE B26/5

Remark: UL MIMO antenna operating on different antenna groups, therefore TAS validation is not required.

Correlation matrix for Spatial TAS implementation for WWAN antenna pairs

Antenna Group	AG0	AG1	AG2
	Ant 0, Ant 6	Ant 1, Ant 5	Ant 2

6. Conducted Power Test Results for Sub-6 TAS validation

6.1 Measurement set-up

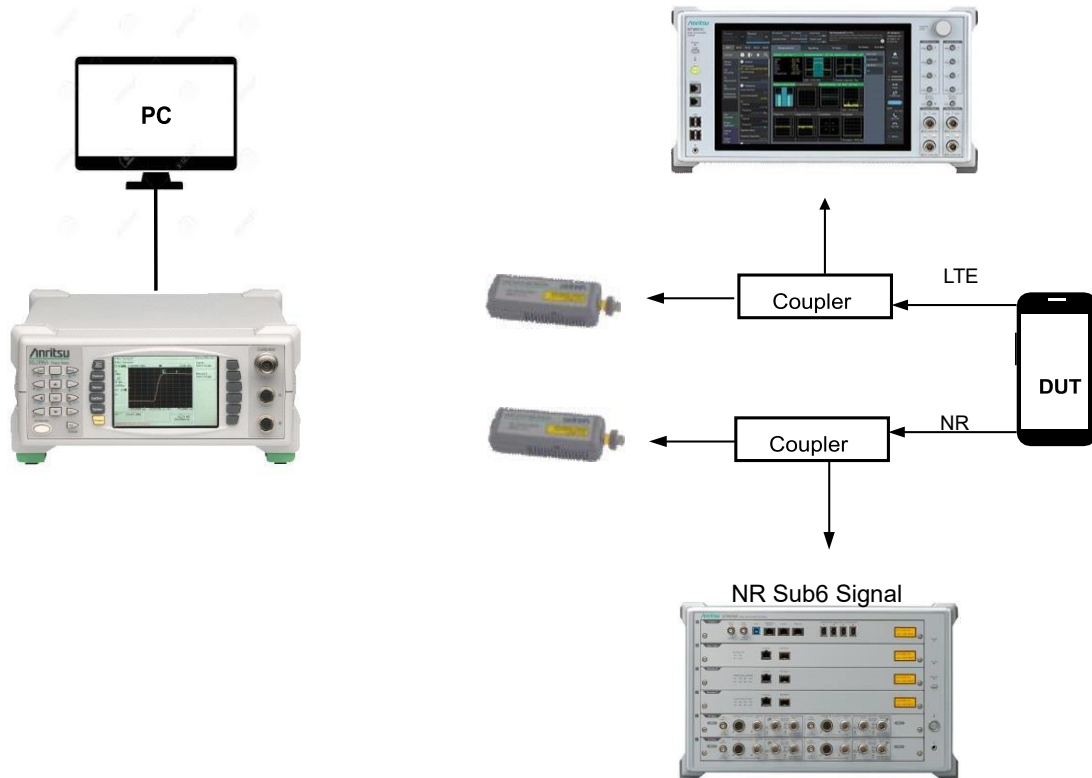


Figure 7.1-1 Test set-up for legacy and sub 6GHz

The test setup for TAS validation with sub-6GHz RATs only is shown in Figure 7.1-1.

Power readings for each active technology are recorded every 100ms and dumped in an excel file. A post- processing tool is used to extract data from the excel file and plot the required metrics such as time-averaged power, SAR and TER values versus time as described in Section 3.3.

In summary, the tests have to be executed as following procedure.

1. Measure conduction sub 6GHz Tx power corresponds to SAR regulation.
2. Execute time-varying test scenarios. And record sub 6GHz power using sub 6GHz power meter equipment.
3. The time interval between subsequent conducted power measurements is 0.1s (typically much less than 1 second)
4. Plot the recorded results over measurement time. And evaluate the results for validation.
5. The required Power level is burst average power level controlled by call box, the power varying measurement correspond to time-average power levels after accounting for duty cycle in the case TDD modulation schemes (e.g. LTE, 5G FR1 TDD bands).

6.2 Measured *Plimit* and *Pmax*

The measured *Plimit* for all the selected radio configurations are listed in Table 7.2.1. *Pmax* was also measured for radio configurations selected for testing time-varying Tx power transmission scenario in order to generate test sequences following the test procedures.

Table 7.2.1 Measured *Plimit* and *Pmax* of selected radio configurations

TC#	Test Scenario	Antenna	Power Index	Test band	Mode	Pmax Setting (dBm)	measured Pmax (dBm)	Plimit Setting (dBm)	Measured Plimit (dBm)	Total Uncertainty (dB)
1	Time varying Tx power case 1	TX1_Ant 0	3	WCDMA B2	RMC 12.2Kbps	24.2	23.48	23.2	22.61	1
2		TX1_Ant 1	3	WCDMA B5	RMC 12.2Kbps	24.2	23.56	18.5	18.51	1
3		TX1_Ant 2	5	LTE B48 pc3	20M_QPSK_1_0	21.5	21.52	20.2	19.37	1
4		TX0_Ant 1	3	LTE B2	20M_QPSK_50_0	24.7	19.06	13.5	12.98	1
5		TX1_Ant 0	4	n30 (SA Mode)	10M_BPSK_25_14	24.2	24.08	23	22.95	1
6		TX1_Ant 2	4	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	24.2	24.17	18.5	18.16	1
7	Time varying Tx power case 2	TX1_Ant 0	3	WCDMA B2	RMC 12.2Kbps	24.2	23.48	23.2	22.61	1
8		TX1_Ant 1	3	WCDMA B5	RMC 12.2Kbps	24.2	23.56	18.5	18.51	1
9		TX1_Ant 2	5	LTE B48 pc3	20M_QPSK_1_0	21.5	21.52	20.2	19.37	1
10		TX0_Ant 1	3	LTE B2	20M_QPSK_50_0	24.7	19.06	13.5	12.98	1
11		TX1_Ant 0	4	n30 (SA Mode)	10M_BPSK_25_14	24.2	24.08	23	22.95	1
12		TX1_Ant 2	4	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	24.2	24.17	18.5	18.16	1
13	Change in power index	TX1_Ant 2	3	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	24.2	24.17	22	22.21	1
		TX1_Ant 2	4	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	24.2	24.17	18.5	18.16	1
14	LTE_Averaging_Time_Window_Change 1	TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	24.2	23.91	20	19.82	1
		TX0_Ant 6	4	LTE B48 pc3	20M_QPSK_50_0	21.6	21.84	19.9	19.54	1.1
15	LTE_Averaging_Time_Window_Change 2	TX0_Ant 6	4	LTE B48 pc3	20M_QPSK_50_0	21.6	21.84	19.9	19.54	1.1
		TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	24.2	23.91	20	19.82	1
16	Call_Disconnect_Reestablishment	TX0_Ant 1	3	LTE B2	20M_QPSK_50_0	24.7	19.06	13.5	12.98	1
17	NSA_FR1_Dominant_Power_Switching	TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	24.2	23.91	20	19.82	1
		TX0_Ant 6	4	n77/n78 pc3 (NSA Mode)	100M_BPSK_135_69	24.7	24.12	19.8	19.93	1
18	NR_TO_LTE_IRAT_HO	TX0_Ant 6	4	n77/n78 pc3 (SA Mode)	100M_BPSK_135_69	24.7	24.12	19.8	19.93	1
		TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	24.2	23.91	20	19.82	1
19	UL CA	TX1_Ant 1	3	LTE B26/5 PCC	15M_QPSK_1_0	24.2	23.38	18.3	17.66	1
				LTE B5 PCC+SCC	10M_QPSK1_0	22.2	20.83		15.03	

Note that the EUT has multiple power indexes to manage the output power for different conditions corresponding to RF exposure conditions in above table, detailed power index trigger conditions are illustrated in the operational description, and 1g and 10g SAR design target are shown in the part 0 report.

6.3 Sub-6 summary test results

TC#	Test Scenario	Antenna	Power Index	Test band	Mode	Total Uncertainty (dB)	Part 1 Measure 1g SAR (W/kg)	1g Time average SAR (W/kg)	deviation (dB)
1	Time varying Tx power case 1	TX1_Ant 0	3	WCDMA B2	RMC 12.2Kbps	1	0.543	0.502	-0.34
2		TX1_Ant 1	3	WCDMA B5	RMC 12.2Kbps	1	0.464	0.431	-0.32
3		TX1_Ant 2	5	LTE B48 pc3	20M_QPSK_1_0	1	0.376	0.367	-0.11
4		TX0_Ant 1	3	LTE B2	20M_QPSK_50_0	1	0.461	0.424	-0.36
5		TX1_Ant 0	4	n30 (SA Mode)	10M_BPSK_25_14	1	0.334	0.311	-0.31
6		TX1_Ant 2	4	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	1	0.573	0.578	0.04
7	Time varying Tx power case 2	TX1_Ant 0	3	WCDMA B2	RMC 12.2Kbps	1	0.543	0.502	-0.34
8		TX1_Ant 1	3	WCDMA B5	RMC 12.2Kbps	1	0.464	0.431	-0.32
9		TX1_Ant 2	5	LTE B48 pc3	20M_QPSK_1_0	1	0.376	0.356	-0.24
10		TX0_Ant 1	3	LTE B2	20M_QPSK_50_0	1	0.461	0.424	-0.36
11		TX1_Ant 0	4	n30 (SA Mode)	10M_BPSK_25_14	1	0.334	0.311	-0.31
12		TX1_Ant 2	4	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	1	0.573	0.578	0.04
13	Change in power index	TX1_Ant 2	3	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	1	0.454	0.53	-0.34
		TX1_Ant 2	4	n77/n78 pc3 (SA Mode)	100M_BPSK_1_1	1	0.573		
14	LTE_Averaging_Time_Window_Change 1	TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	1	0.364	0.605	0.50
		TX0_Ant 6	4	LTE B48 pc3	20M_QPSK_50_0	1.1	0.539		
15	LTE_Averaging_Time_Window_Change 2	TX0_Ant 6	4	LTE B48 pc3	20M_QPSK_50_0	1.1	0.539	0.578	0.30
		TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	1	0.364		
16	Call_Disconnect_Reestablishment	TX0_Ant 1	3	LTE B2	20M_QPSK_50_0	1	0.461	0.419	-0.41
17	NSA_FR1_Dominant_Power_Switching	TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	1	0.364	0.526	0.28
		TX0_Ant 6	4	n77/n78 pc3 (NSA Mode)	100M_BPSK_135_69	1	0.493		
18	NR_TO_LTE_IRAT_HO	TX0_Ant 6	4	n77/n78 pc3 (SA Mode)	100M_BPSK_135_69	1	0.493	0.481	-0.11
		TX1_Ant 0	4	LTE B7	20M_QPSK_1_0	1	0.364		
19	UL CA	TX1_Ant 1	3	LTE B26/5 PCC	15M_QPSK_1_0	1	0.427	0.38	-0.51
				LTE B5 PCC+SCC	10M_QPSK1_0		0.331		

6.4 Time-varying Tx power measurement results

Following the test procedure in Section 3, the conducted Tx power measurement results for all selected test cases are listed in this section. In all conducted Tx power plots, the blue line shows the measured instantaneous power using the power meter, the red line shows the time-averaged Tx power and yellow line shows the Plimit value corresponding to design target. In all SAR plots, the dotted blue line shows the time-averaged 1gSAR while the red line shows the corresponding FCC limit of 1.6W/Kg. Time-varying Tx power measurements were conducted for TC#1 - 12 in Table 7.2.1 by generating the test sequence A or B given in Appendix.

7.3.1 TC01: WCDMA B2_Time_Varying_Tx_Power_Case_1

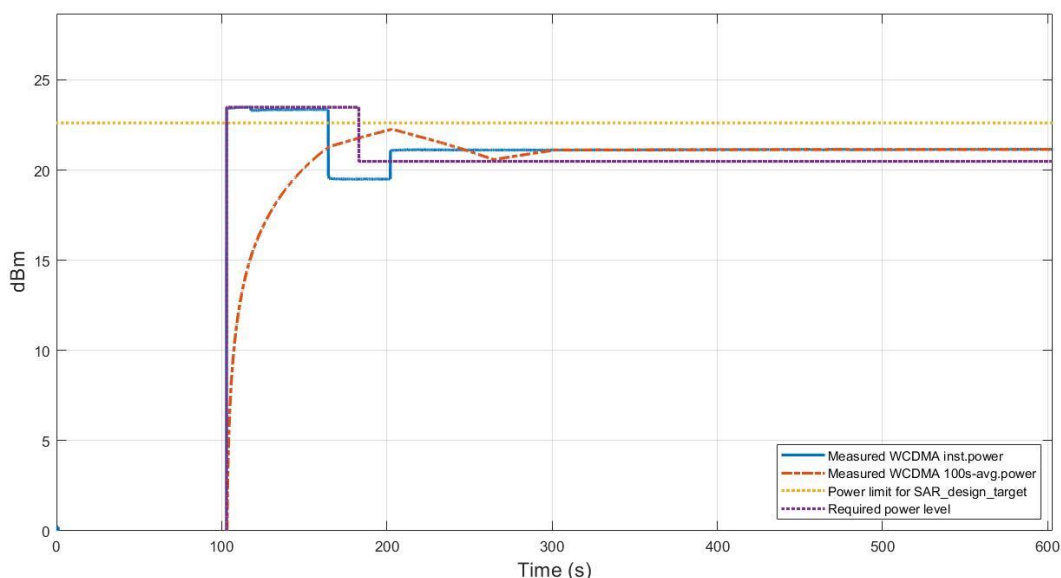


Figure 7.3-1 Time average conducted power

Figure 7.3-1 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR FCC Limit value. As shown in Figure 7.3-1, it is confirmed for time- average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is smaller than the target power, and it will saturate to target power with little margin. Figure 7.3-2 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

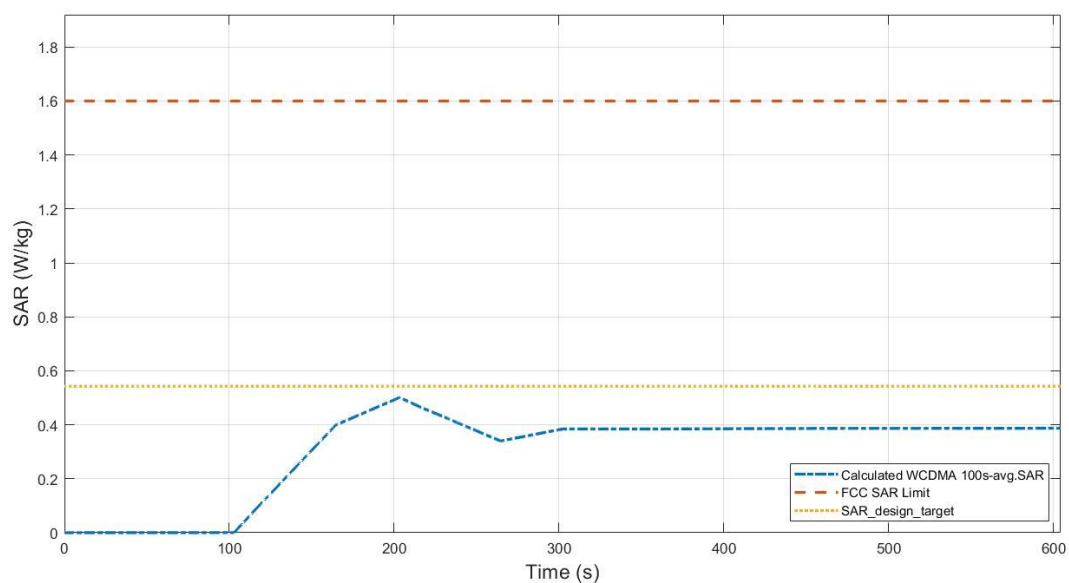


Figure 7.3-2 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.502 W/kg
Device uncertainty	1 dB

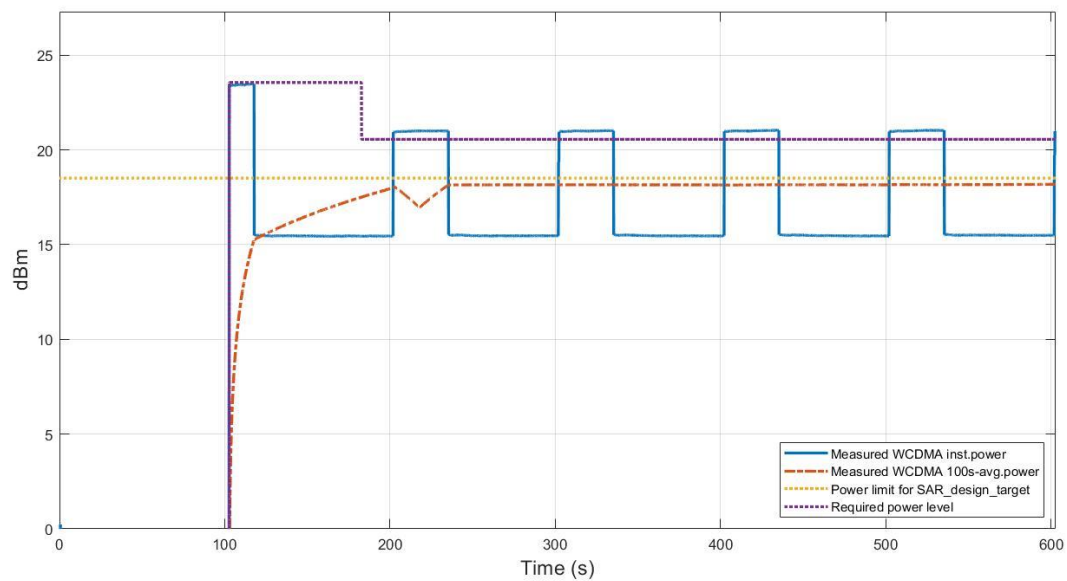
7.3.2 TC02: WCDMA B5_Time_Varying_Tx_Power_Case_1

Figure 7.3-3 Time-average conducted power

Figure 7.3-3 shows the instantaneous and time-averaged Tx power for this test. As shown in Figure 7.3-3, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of Plimit. Figure 7.3-4 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

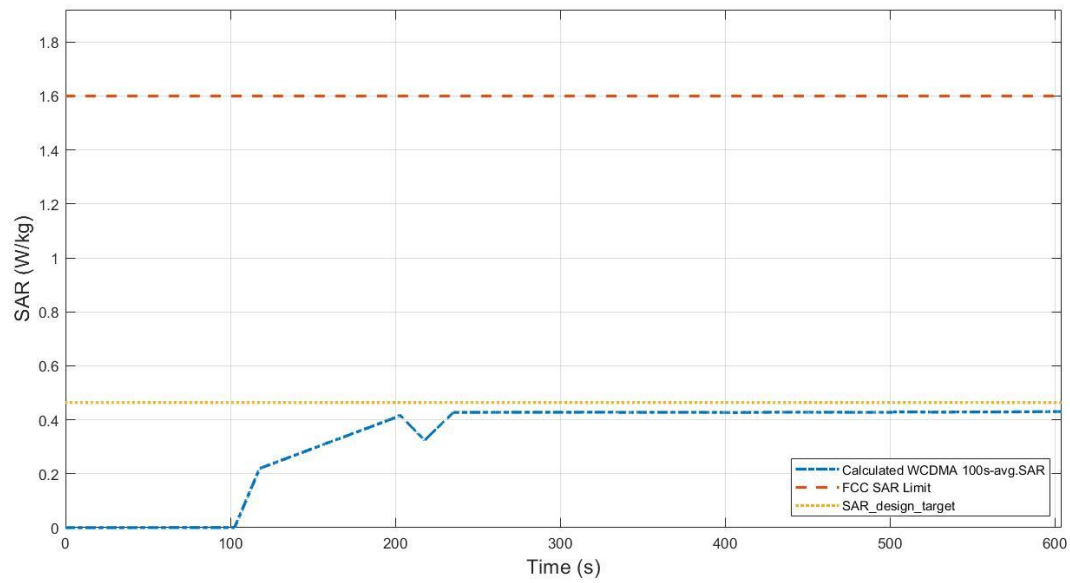


Figure 7.3-4 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.431 W/kg
Device uncertainty	1 dB

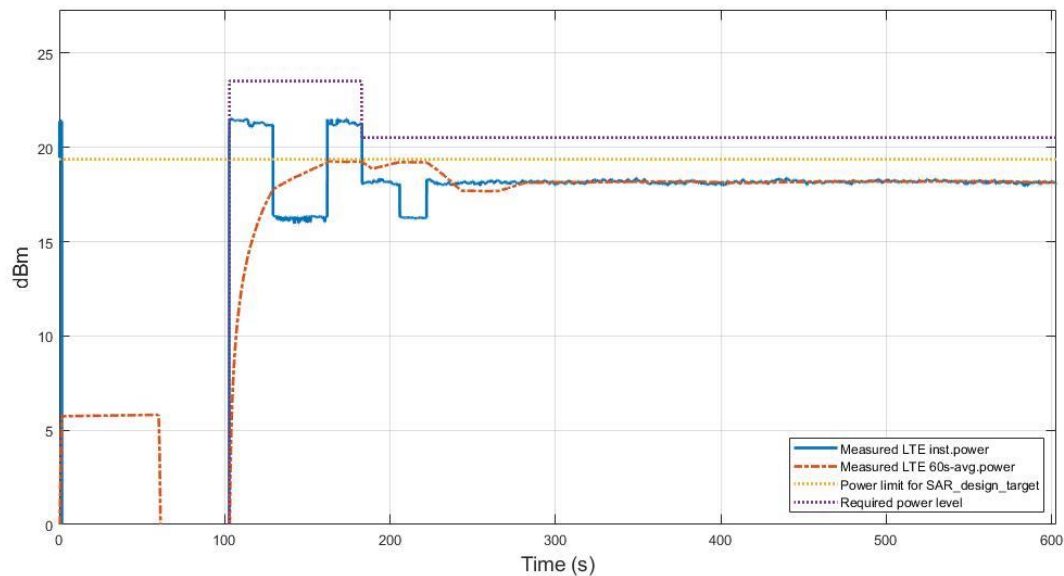
7.3.3 TC03: LTE Band 48_Time_Varying_Tx_Power_Case_1


Figure 7.3-5 Time-average conducted power

Figure 7.3-5 shows the instantaneous and time-averaged Tx power for this test. As shown in Figure 7.3-5, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of P_{limit}. Figure 7.3-6 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

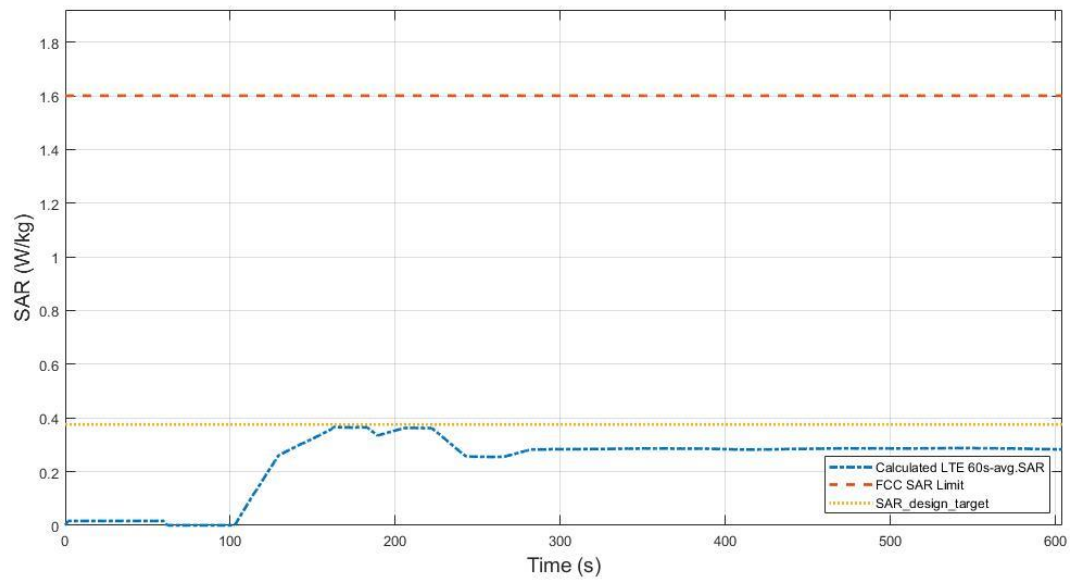


Figure 7.3-6 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.367 W/kg
Device uncertainty	1 dB

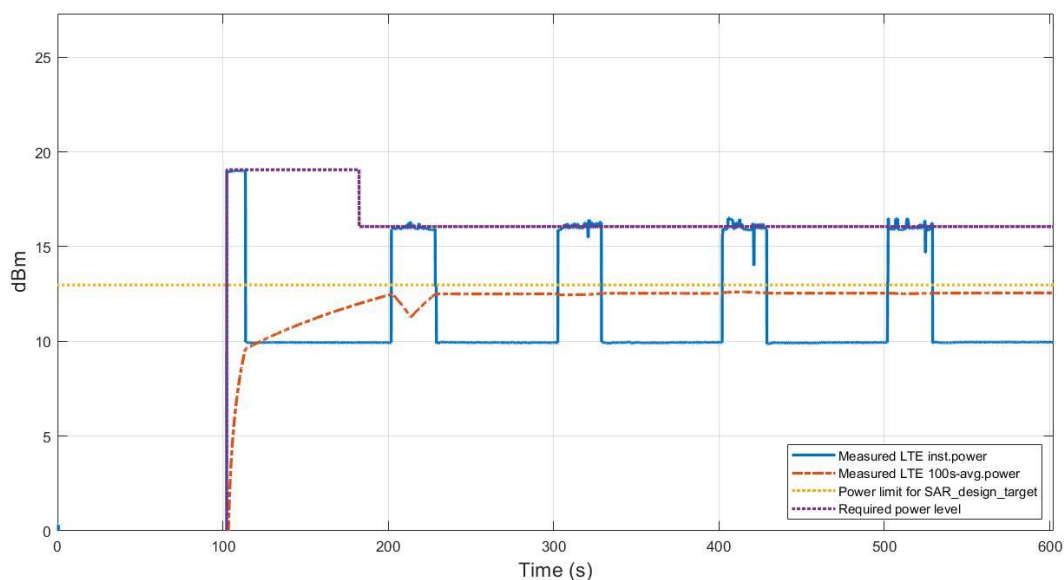
7.3.4 TC04: LTE Band 2_Time_Varying_Tx_Power_Case_1

Figure 7.3-7 Time-average conducted power

Figure 7.3-7 shows the instantaneous and time-averaged Tx power for this test. As shown in Figure 7.3-7, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of Plimit. Figure 7.3-8 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

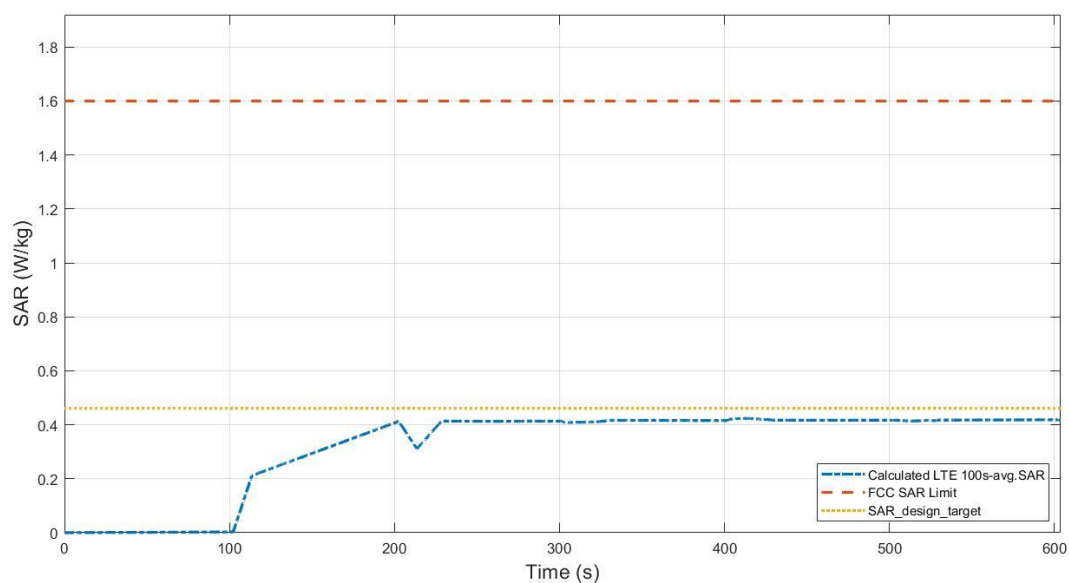


Figure 7.3-8 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.424 W/kg
Device uncertainty	1 dB

7.3.5 TC05: FR1 n30 SA mode_Time_Varying_Tx_Power_Case_1

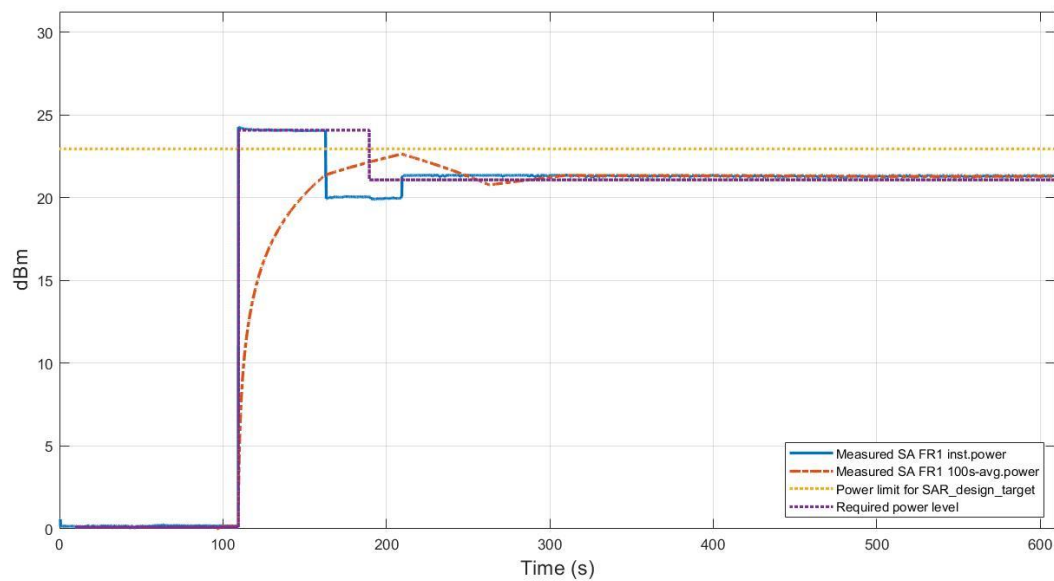


Figure 7.3-9 Conducted Tx power

Figure 7.3-9 shows the instantaneous and time-averaged Tx power for this test. As shown in Figure 7.3-9, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of Plimit. Figure 7.3-10 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

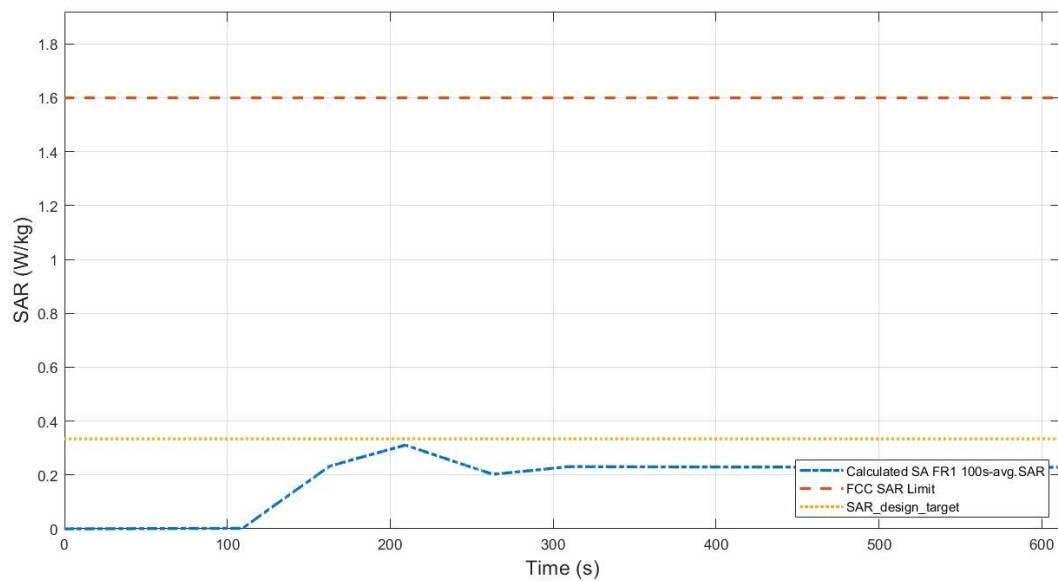


Figure 7.3-10 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.311 W/kg
Device uncertainty	1 dB

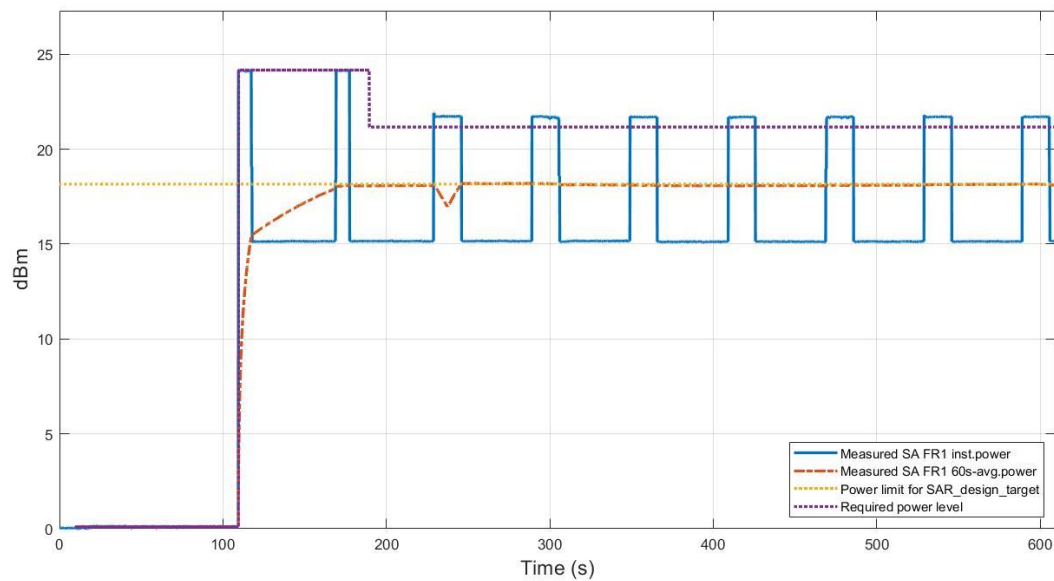
7.3.6 TC06: FR1 n77/n78 SA mode_Time_Varying_Tx_Power_Case_1

Figure 7.3-11 Conducted Tx power

Figure 7.3-11 shows the instantaneous and time-averaged Tx power for this test. As shown in Figure 7.3-11, it is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of Plimit. Figure 7.3-12 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

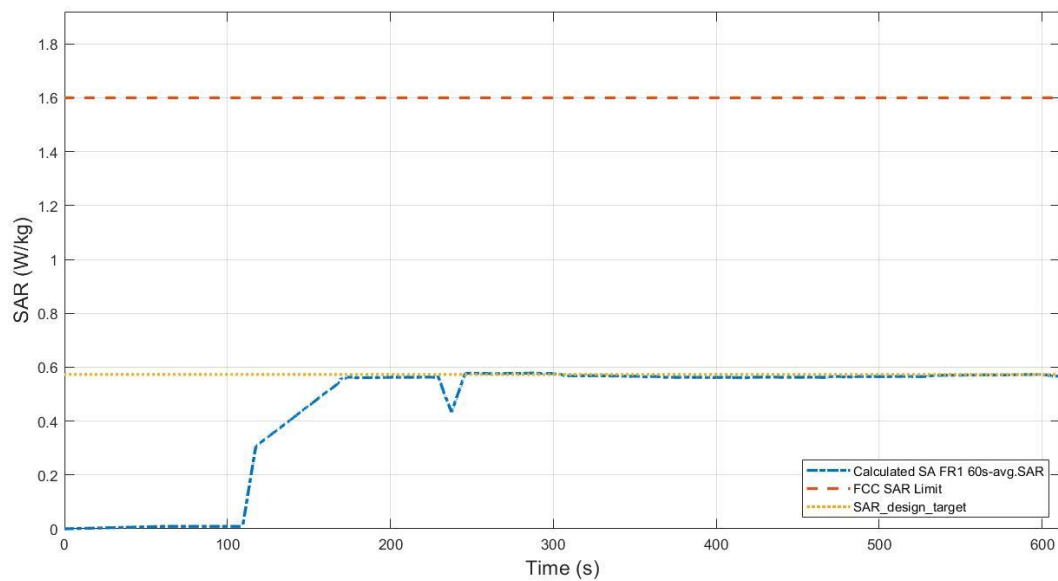


Figure 7.3-12 Total time-averaged SAR in F_TC04

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.578 W/kg
Device uncertainty	1 dB

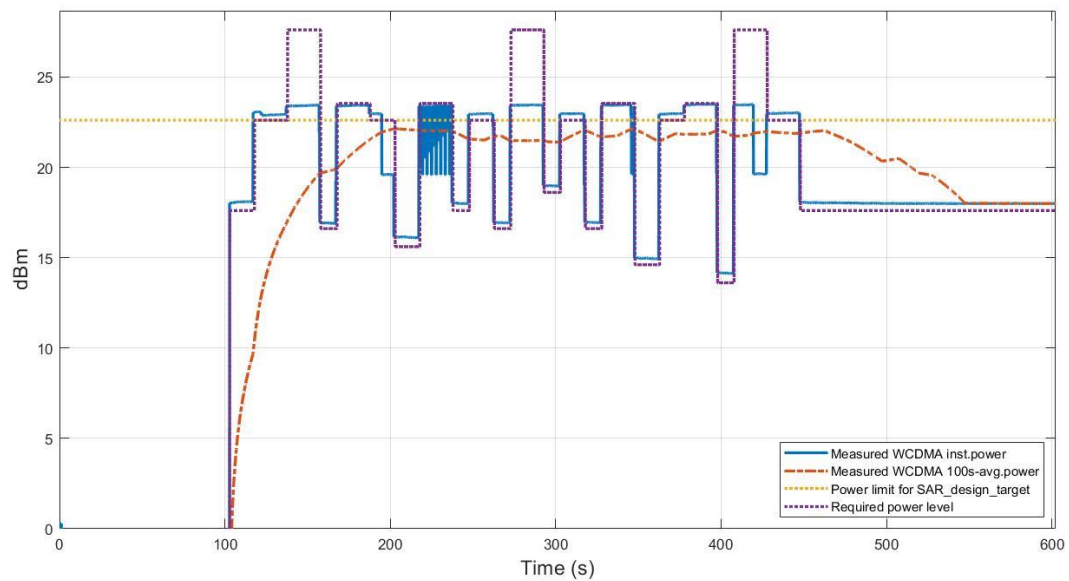
7.3.7 TC07: WCDMA B2_Time_Varying_Tx_Power_Case_2


Figure 7.3-13 Conducted Tx power

Figure 7.3-13 shows the instantaneous and time-averaged Tx power with test sequence B. Figure 7.3-14 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

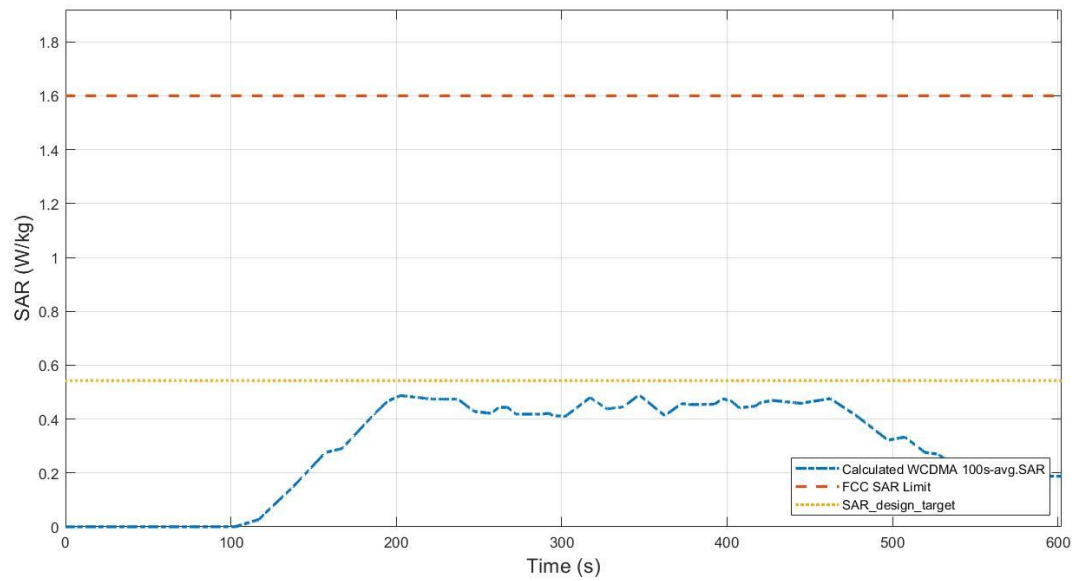


Figure 7.3-14 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.502 W/kg
Device uncertainty	1 dB

7.3.8 TC08: WCDMA B5_Time_Varying_Tx_Power_Case_2

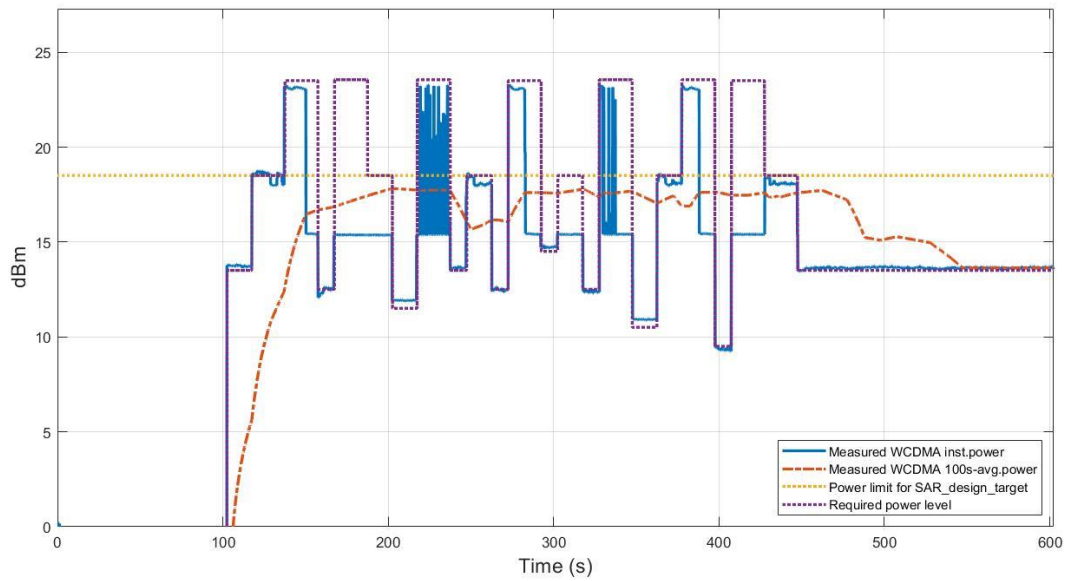


Figure 7.3-15 Conducted Tx power

Figure 7.3-15 shows the instantaneous and time-averaged Tx power with test sequence B. Figure 7.3-16 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

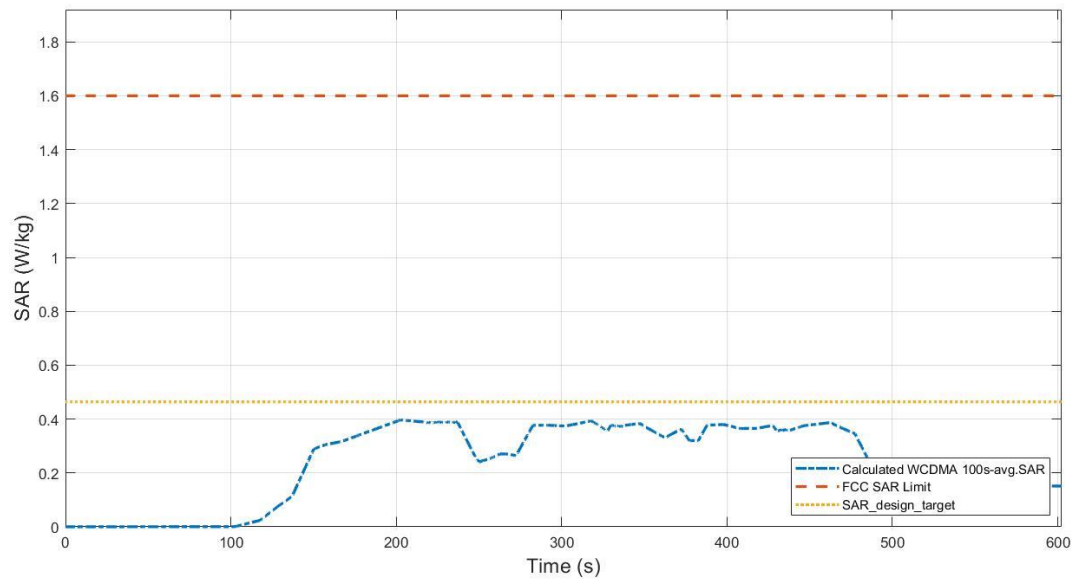


Figure 7.3-16 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.431 W/kg
Device uncertainty	1 dB

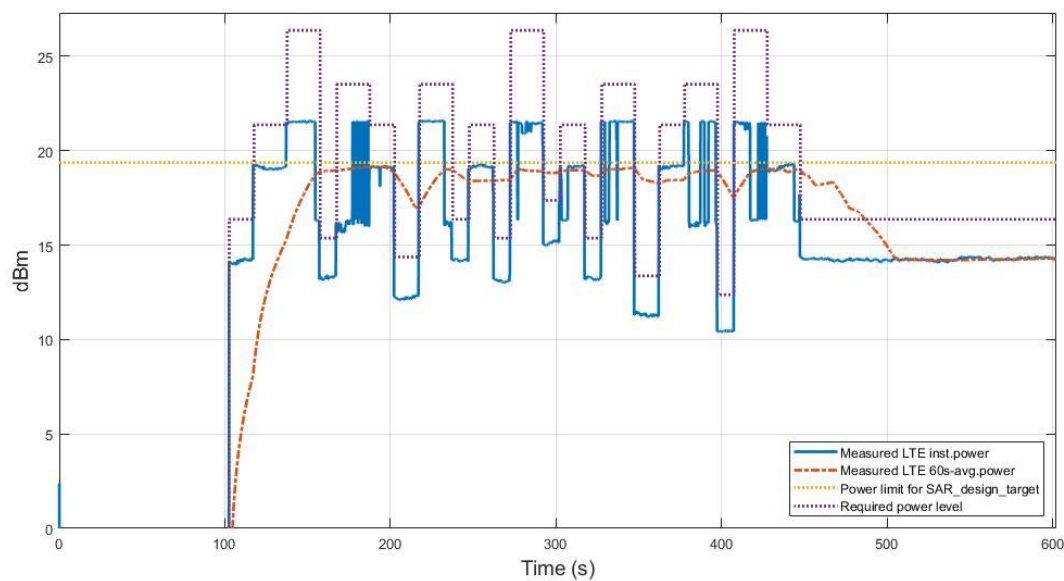
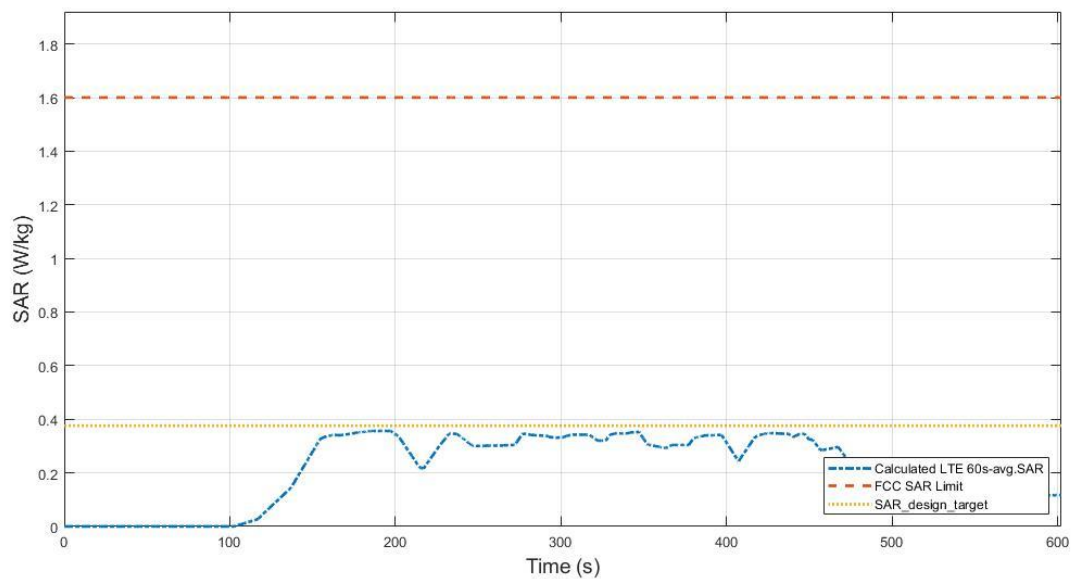
7.3.9 TC09: LTE Band 48_Time_Varying_Tx_Power_Case_2


Figure 7.3-17 Conducted Tx power

Figure 7.3-17 shows the instantaneous and time-averaged Tx power with test sequence B. Figure 7.3-18 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.


Figure 7.3-18 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.356 W/kg
Device uncertainty	1 dB

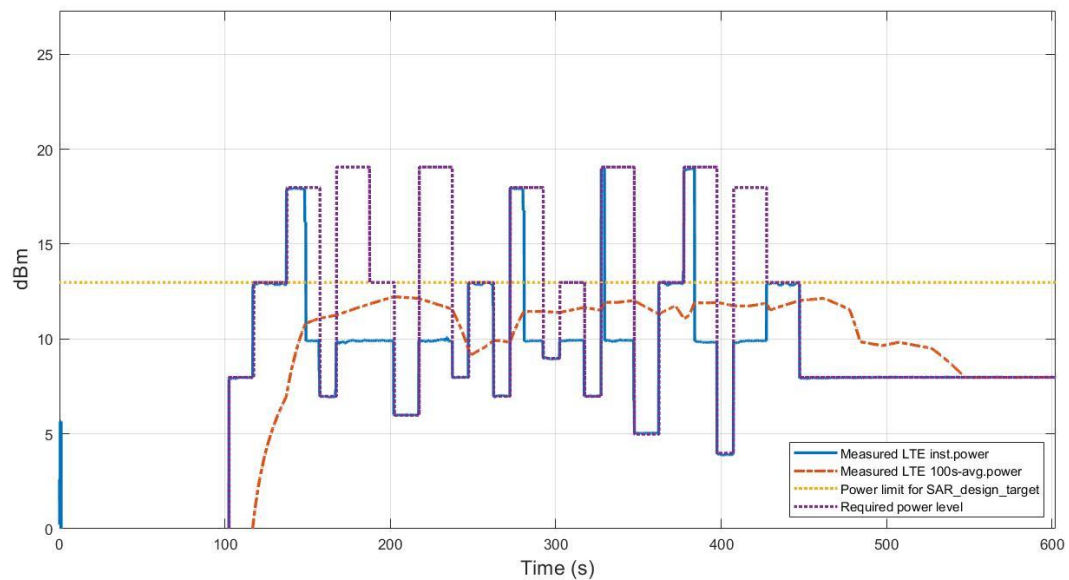
7.3.10 TC10: LTE Band 2_Time_Varying_Tx_Power_Case_2

Figure 7.3-19 Conducted Tx power

Figure 7.3-19 shows the instantaneous and time-averaged Tx power with test sequence B. Figure 7.3-20 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

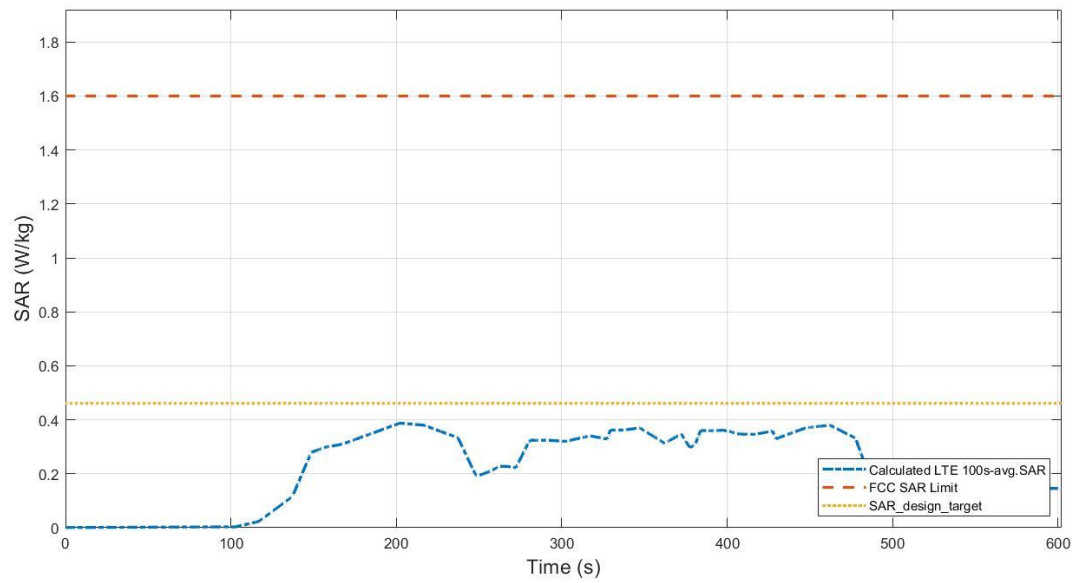


Figure 7.3-20 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.424 W/kg
Device uncertainty	1 dB

7.3.11

TC11: FR1 n30 SA mode _Time_Varying_Tx_Power_Case_2

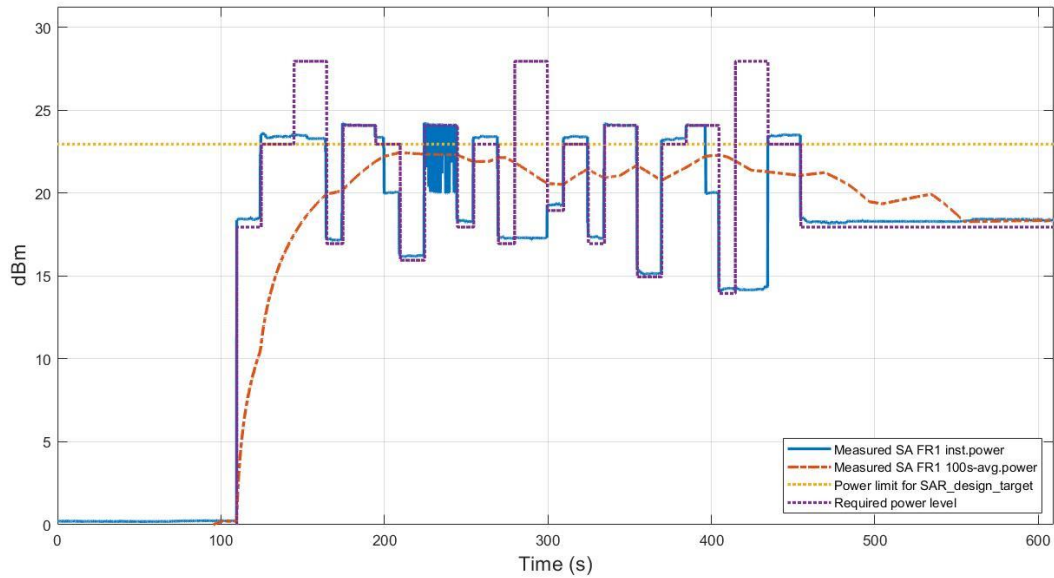


Figure 7.3-21 Conducted Tx power

Figure 7.3-21 shows the instantaneous and time-averaged Tx power with test sequence B. Figure 7.3-22 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

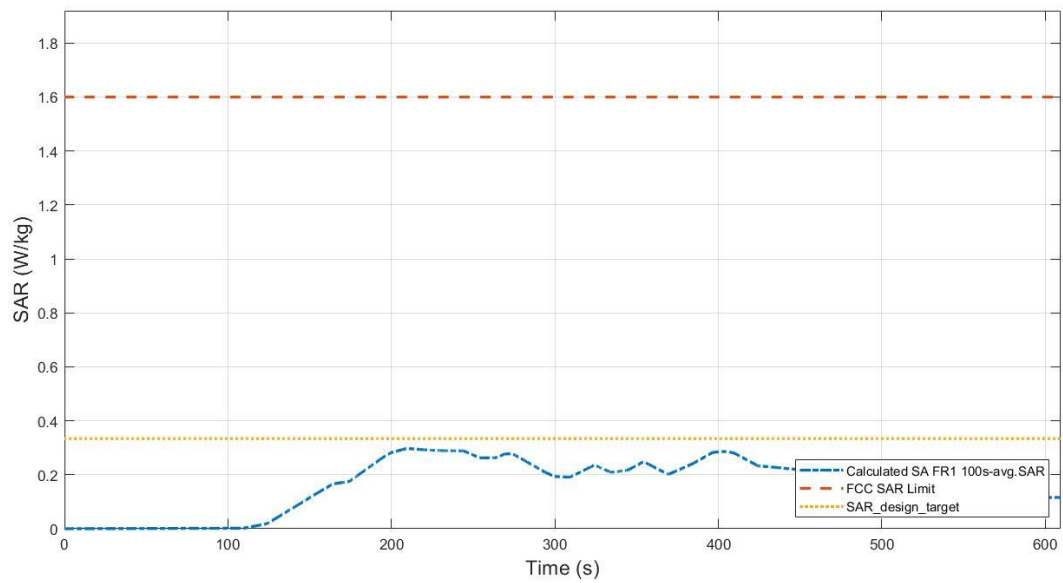


Figure 7.3-22 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.311 W/kg
Device uncertainty	1 dB

7.3.12

TC12: FR1 n77/n78 SA mode_Time_Varying_Tx_Power_Case_2

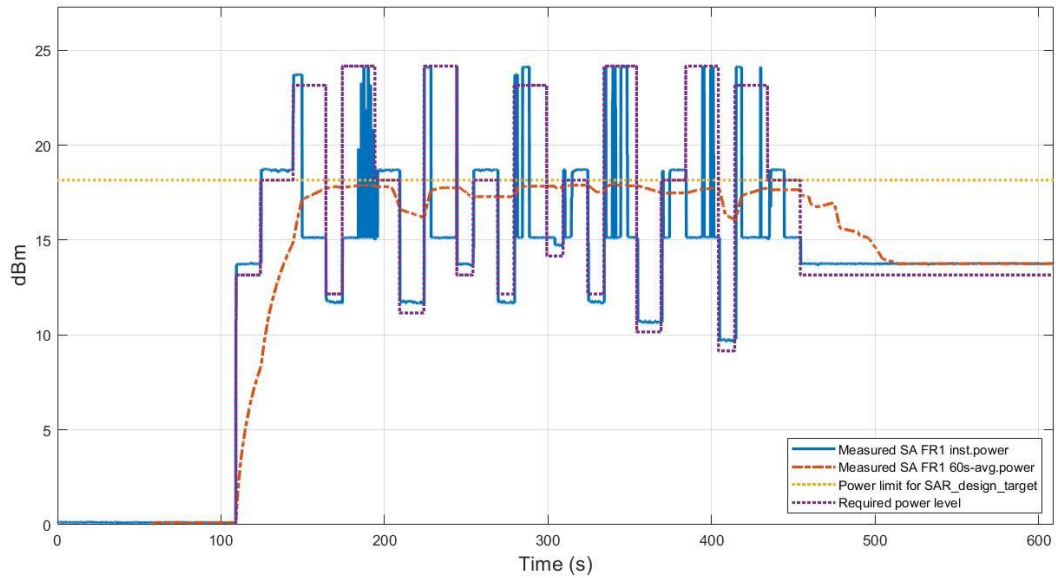


Figure 7.3-23 Conducted Tx power

Figure 7.3-23 shows the instantaneous and time-averaged Tx power with test sequence B. Figure 7.3-24 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg.

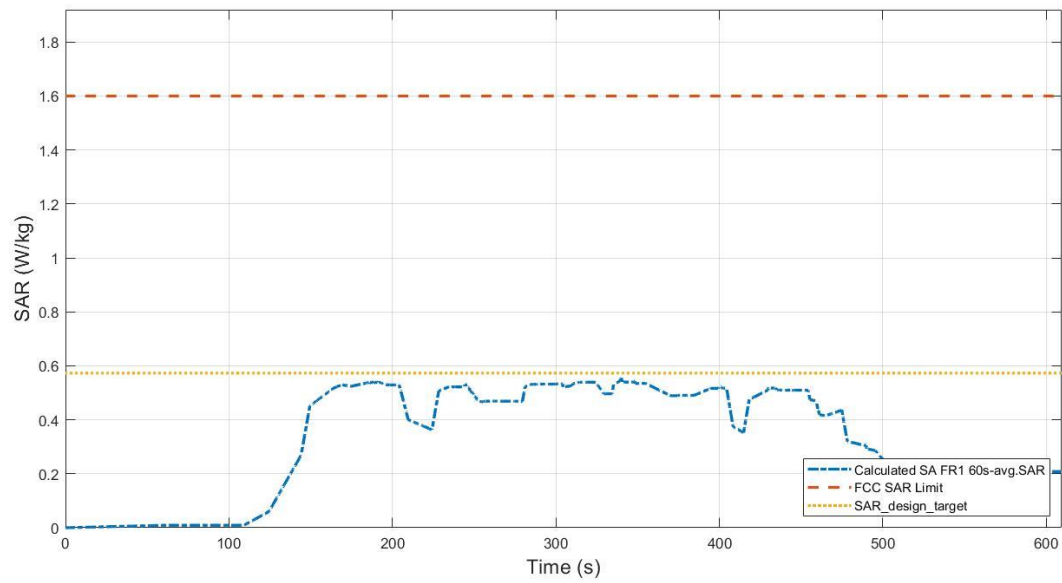


Figure 7.3-24 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.578 W/kg
Device uncertainty	1 dB

6.5 Change in Power Index

The test results in this section are obtained following the procedure in Section 3. The test cases correspond to TC#13 in Table 7.2.1.

7.4.1 TC13: SA_FR1 n77/n78_RF_SAR_Index_Change

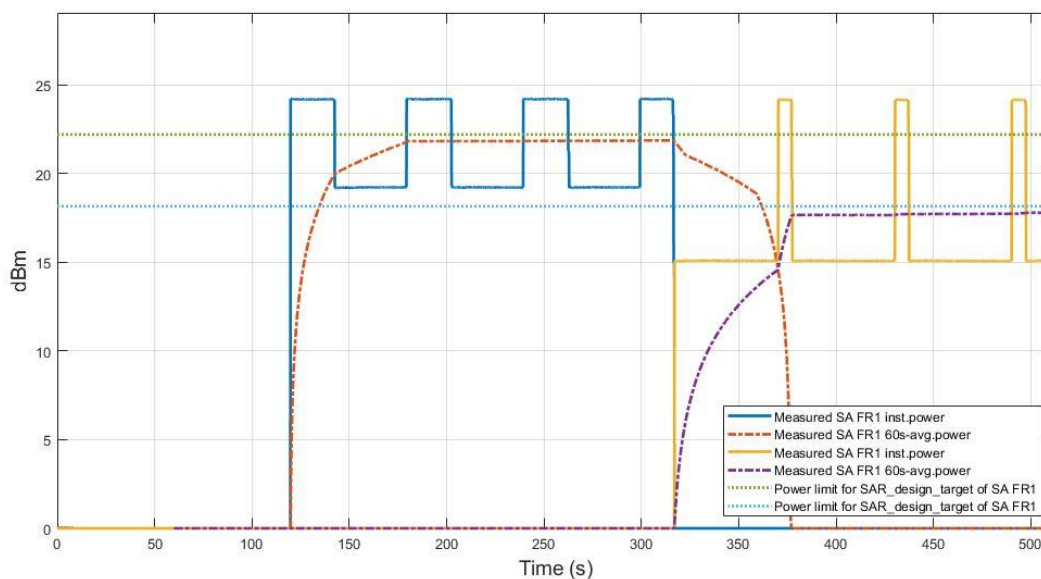


Figure 7.4-1 Conducted Tx power for SAR states change

Figure 7.4-1 shows the instantaneous and time-averaged conducted Tx power for the duration of the test. Figure 7.4-2 shows the time-averaged 1gSAR value for each of power index 3 and power index 4 value, as well as the total SAR value.

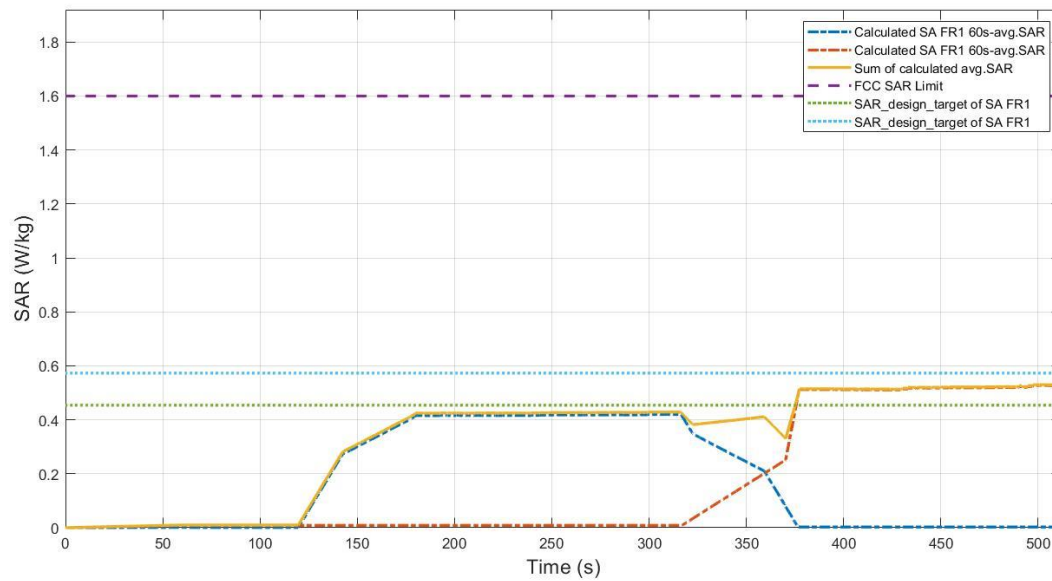


Figure 7.4-2 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max sum of calculated average SARs (yellow curve)	0.530W/kg
Device uncertainty	1 dB

6.6 Change in band/time-window test results

The test results in this section are obtained following the procedure in Section 3.3.2. The test cases correspond to TC#14-15 in Table 7.2.1.

7.5.1 TC14: LTE_Averaging_Time_Window_Change_1 (LTE Band 7 ant 0 to LTE Band 48 ant 6)

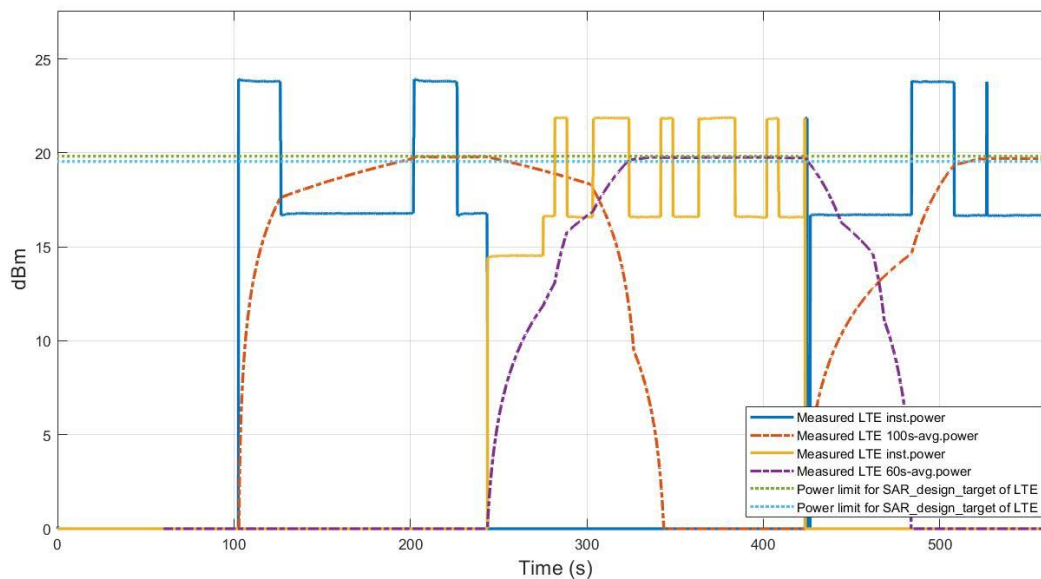


Figure 7.5-1 Conducted Tx power for SAR window change

Figure 7.5-1 shows the instantaneous and time-averaged conducted Tx power for both LTE Band 7 and Band 48 for the duration of the test. Figure 7.5-2 shows the time-averaged 1gSAR value for each of Band 7 and Band 48, as well as the total SAR value. We can see that the total 1gSAR is higher during the band transitions, but is always under the total FCC limit of 1.6W/Kg.

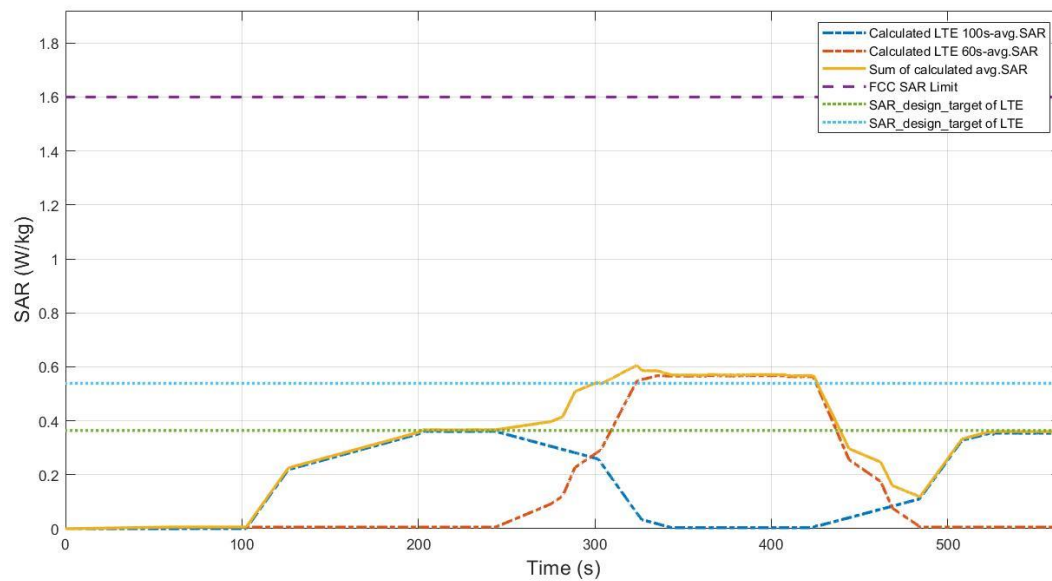


Figure 7.5-2 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max sum of calculated average SARs (yellow curve)	0.605 W/kg
Device uncertainty	1.1dB

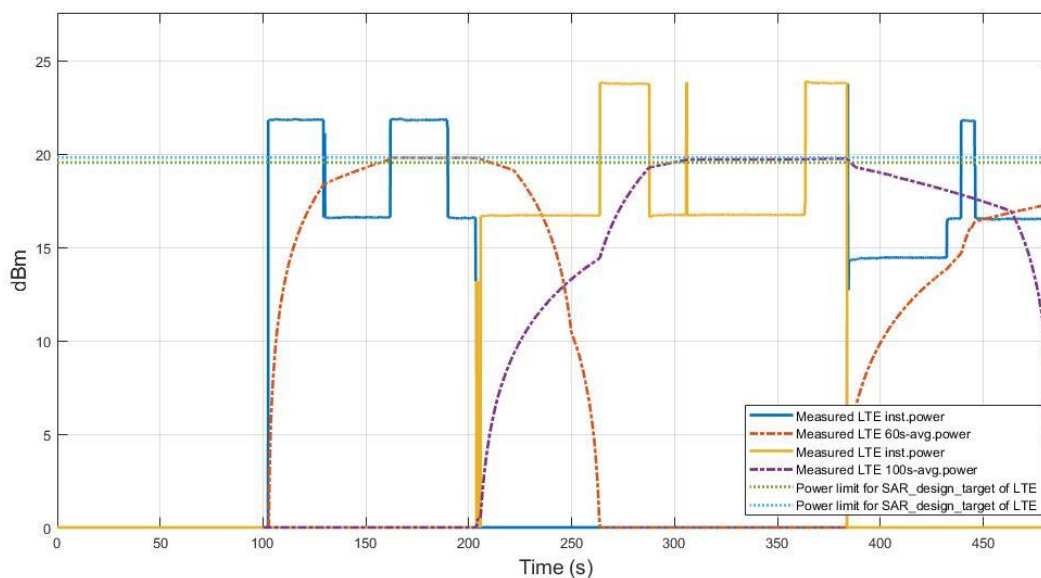
7.5.2 TC15: LTE_Averaging_Time_Window_Change_2 (LTE Band 48 ant 6 to LTE Band 7 ant 0)

Figure 7.5-3 Conducted TxPower in SAR Window Change test

Figure 7.5-3 shows the instantaneous and time-averaged conducted Tx power for both LTE Band 7 and Band 48 for the duration of the test.. Figure 7.5-4 shows the time-averaged 1gSAR value for each of Band 7 and Band 48, as well as the total SAR value. We can see that the total 1gSAR is higher during the band transitions, but is always under the total FCC limit of 1.6W/Kg.

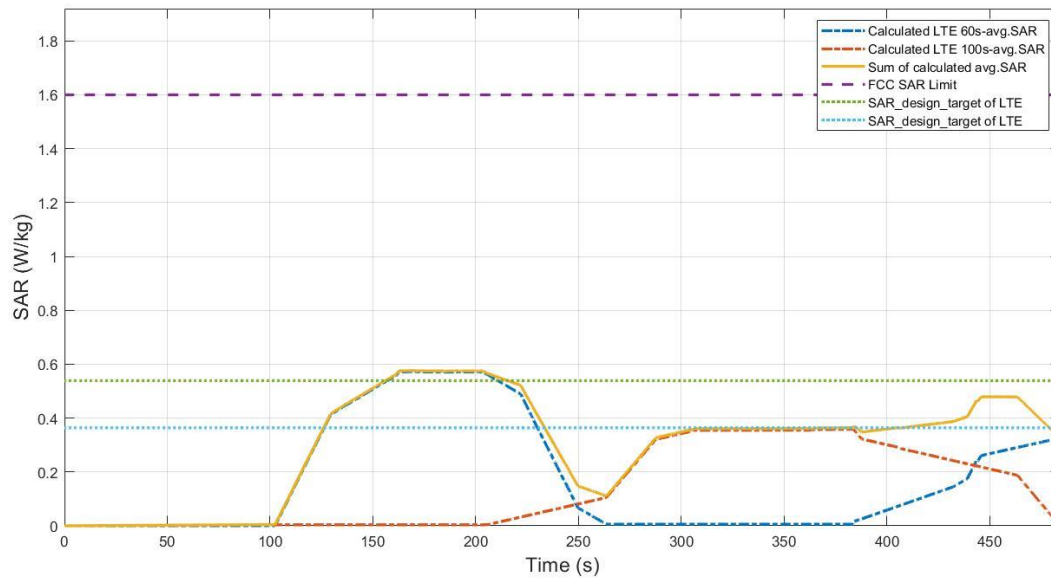


Figure 7.5-4 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max sum of calculated average SARs (yellow curve)	0.578 W/kg
Device uncertainty	1.1 dB

6.7 Change in call test results

The test results in this section are obtained following the procedure in Section 3. The test case corresponds to TC#16 in Table 7.2.1.

7.6.1 TC16: LTE Band 2_Call_Disconnect_Reestablishment

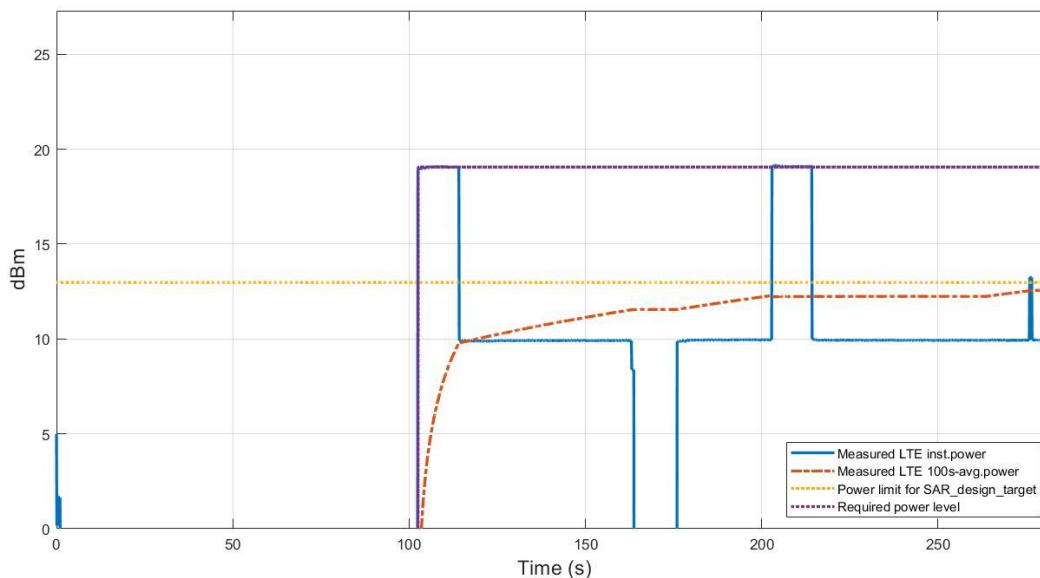
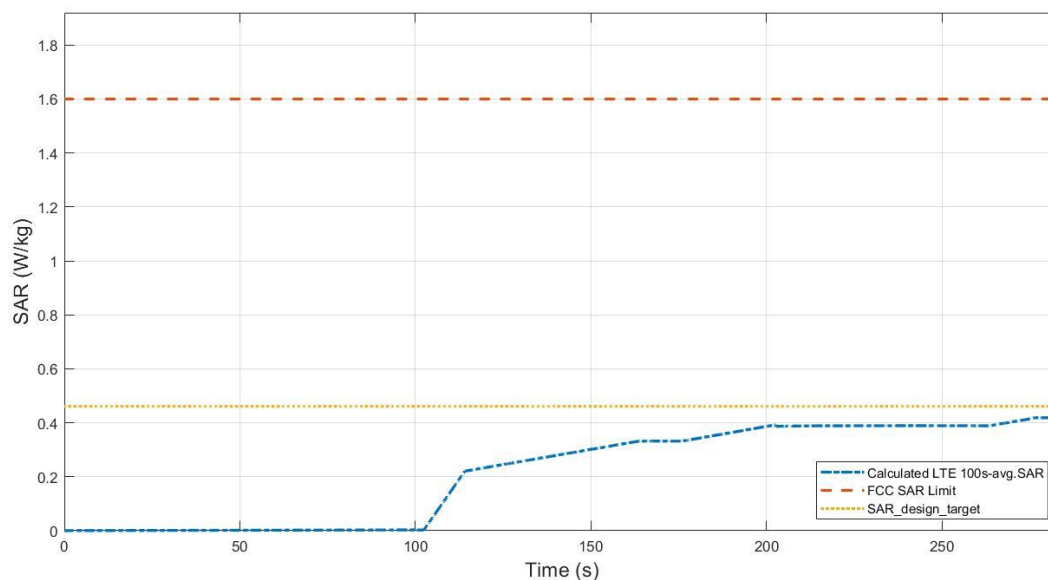


Figure 7.6-1 Conducted Tx power in Call_Disconnect_Reestablishment

Figure 7.6-1 shows the instantaneous and time-averaged Tx power for this test. The call disconnected around 160s and resumed after 10s. It is confirmed for time-average Tx power that the FCC limit was not exceeded, and that the averaged Tx power is lower than the value of P_{limit}. Figure 7.6-2 shows the plot of calculated time-averaged 1gSAR for this test demonstrating that exposure is well below the FCC limit of 1.6W/Kg. Looking at the results, it can be seen that even if transmission is stopped due to a call drop, the SAR value measured for a period of time window is stored in the window section and is continuously checked.


Figure 7.6-2 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max time average 1gSAR (blue curve)	0.419 W/kg
Device uncertainty	1 dB

6.8 Switch in SAR exposure test results

The test results in this section are obtained following the procedure in Section 3. The test cases correspond to TC#17 in Table 7.2.1.

6.8.1 TC17: NSA_FR1_Dominant_Power_Switching (ENDC LTE Band 7_n77/n78)

In this LTE Band 7+FR1 n77 NSA scenario, we first establish LTE and NR call. In the first part of test, LTE is sent to lowest transmit power using “ALL DOWN” power control commands from call box while NR is sent to maximum power using “ALL UP” power control commands from call box. This would correspond to FR1 dominant SAR scenario and lasts about 110s. In the second part of test, LTE is sent “ALL UP” commands and transmissions are continued, resulting in LTE+FR1 SAR scenario lasting another 110s. In the third part of test, NR is sent “ALL DOWN” power control commands so that it becomes an FR1 dominant SAR scenario for 110s. Finally, both LTE and NR connections are released.

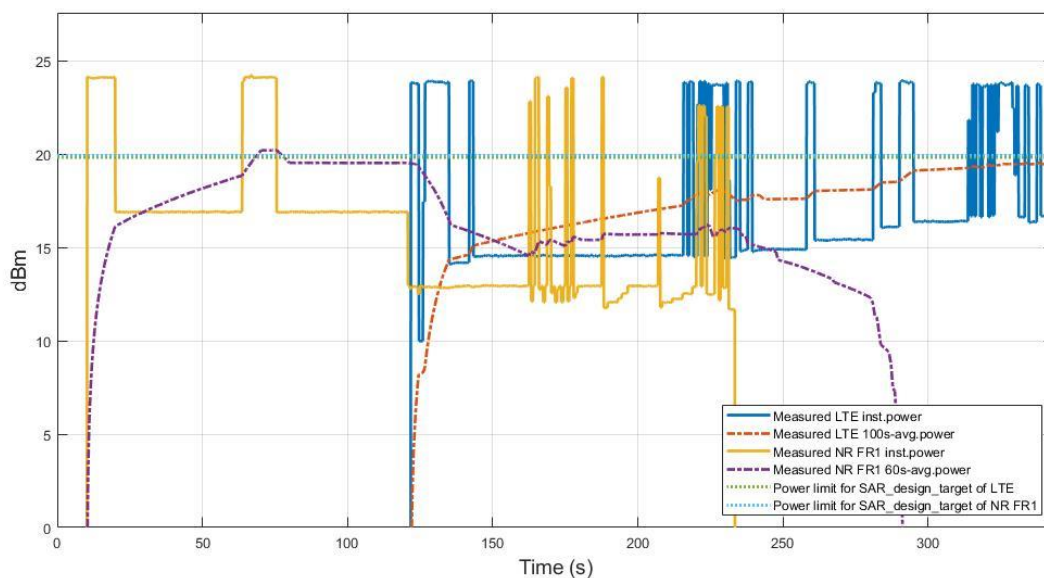


Figure 7.7-1 Time average SAR of LTE B7 and FR1 n77/n78 in EN-DC case

Figure 7.8-1 shows the instantaneous and time-averaged Tx power for both LTE band B7 and NR FR1 band n77/n78 versus time. When both LTE and FR1 operate, the SAR value was the highest instantaneously, but it can be seen that sum of average power in LTE and FR1 decreases again as soon as it is turned off. Figure 7.7-2 shows the computed time-averaged SAR value for LTE and FR1 as well as the sum. It was confirmed that algorithm operated under the SAR design target + total uncertainty, while also being under the FCC limit of 1.6W/Kg at all times. After the operation of FR1 is turned off, it can also be seen that the average power of LTE increases.

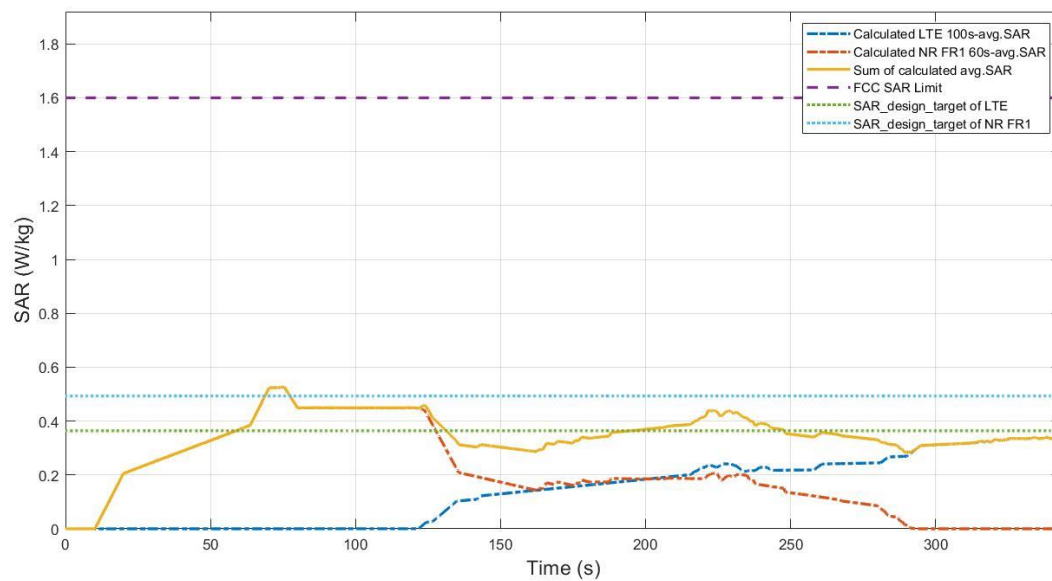


Figure 7.7-2 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max sum of calculated average SARs (yellow curve)	0.526 W/kg
Device uncertainty	1 dB

6.9 Re-selection in call test results

The test results in this section are obtained following the procedure in Section 3. The test cases correspond to TC#18 in Table 7.2.1.

7.8.1 TC18: FR1 n77/n78 to LTE Band 7 IRAT Re-selection

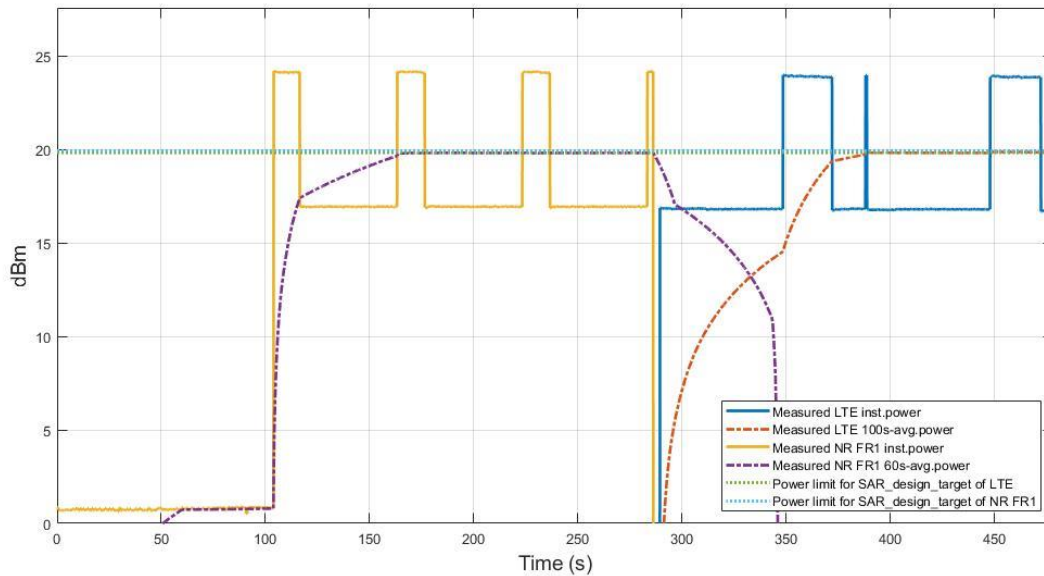


Figure 7.8-1 Conducted Tx power for SAR IRAT re-selection

Figure 7.8-1 shows the instantaneous and time-averaged conducted Tx power for both LTE Band 7 and NR FR1 n77/n78 for the duration of the test. Around time stamp of ~280s, a RAT re-selection from LTE Band 7 to NR FR1 n77/n78 was executed, resulting in reduction of time-averaged power of Band 7 and simultaneous increase in time-averaged power of n77/n78. Figure 7.8-2 shows the time-averaged 1gSAR value for each of LTE Band 7 and NR FR1 n77/n78, as well as the total SAR value.

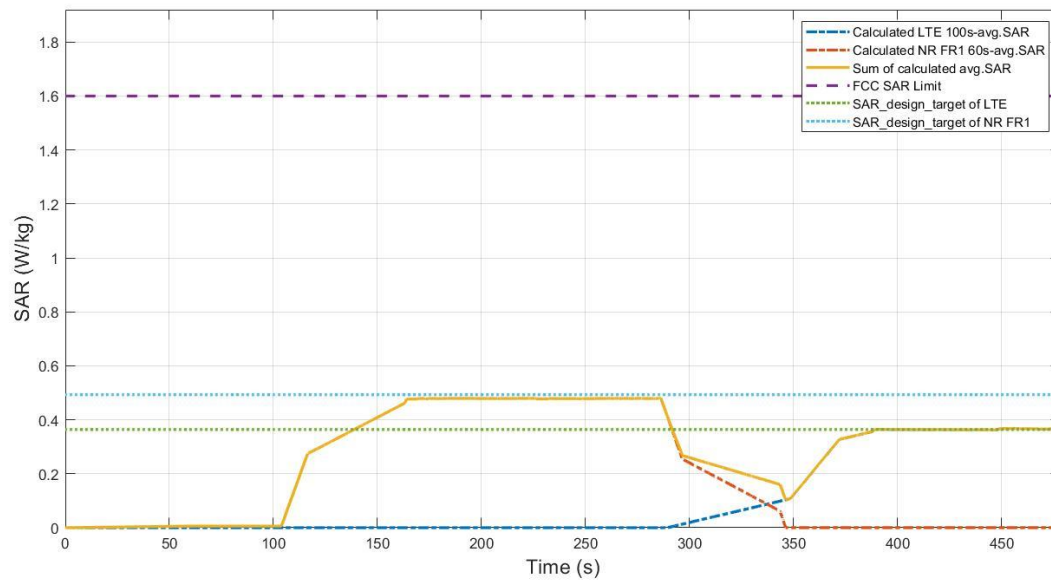


Figure 7.8-2 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max sum of calculated average SARs (yellow curve)	0.481 W/kg
Device uncertainty	1 dB

6.10 LTE Uplink CA

The test results in this section are obtained following the procedure in Section 3. The test cases correspond to TC#18 in Table 7.2.1.

6.10.1 TC20: LTE_UL_CA (LTE Band 26/5)

Figure 7.10-1 shows the conducted Tx power plot with calculated time-averaged power based on the measured instantaneous Tx power with 1gSAR FCC Limit value. In this test, SAR_design_target would be 0.427W/kg at 17.66dBm. The setting value and measured values are described in Table 7.2.1. An MPR of 2dB is configured within this band so with 100% duty cycle the maximum power should be reaching 24.2dBm.

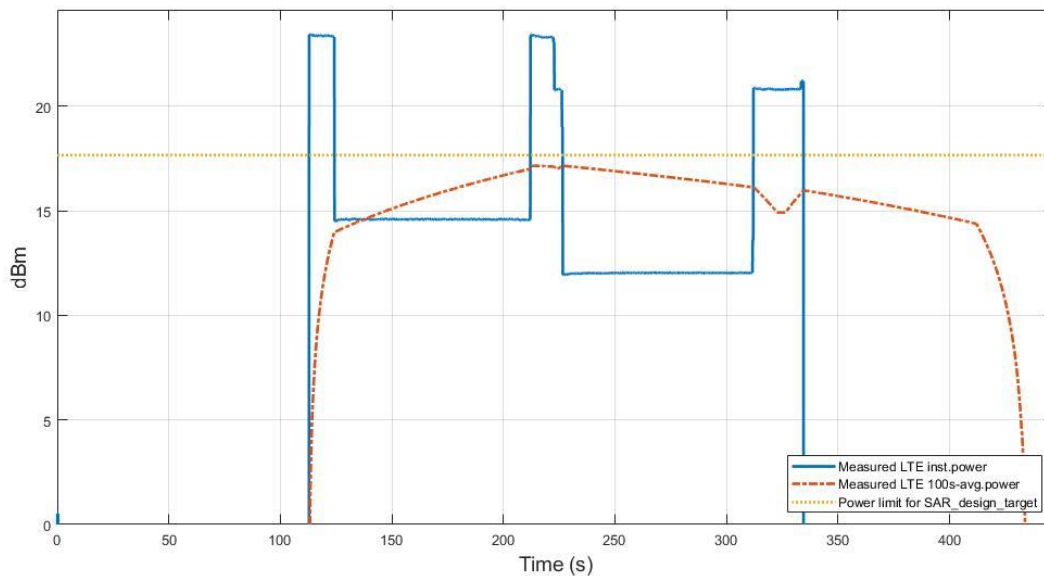


Figure 7.9-1 Conducted transmitted power of LTE Band 26/5 in UL CA

Next after 120s, an intra-band CA is configured (CA_7C) where a new CC is added and the transmission is continued for another 120s. As shown in Figure 7.9-1, the total power of the two CC is kept almost the same as in the single CC transmission. Average power in Figure 7.9-1 assures the compliance of the average power of the transmitted signal which is below 17.66dBm and consequently the average SAR in Figure 7.9-2 is below 1W/kg which is below the FCC limit of 1.6W/kg

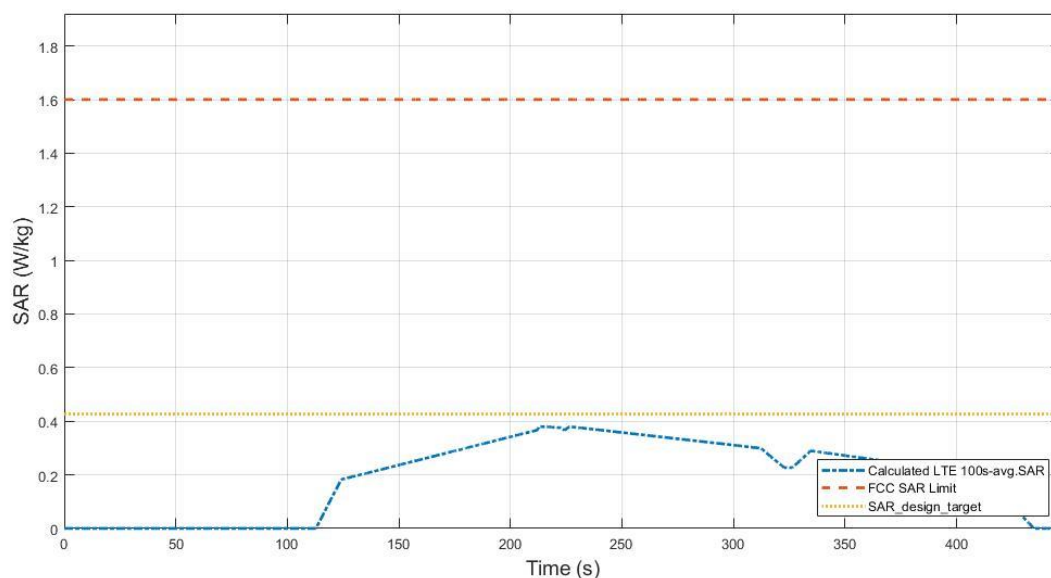


Figure 7.10-2 Total time-averaged SAR

FCC 1gSAR limit	1.6 W/kg
Max sum of calculated average SARs (blue curve)	0.380 W/kg
Device uncertainty	1 dB

7. Conclusions

Samsung S.LSI TAS feature employed in this product has been validated through the conducted power measurement for sub-6, radiated power measurement for FR2 as demonstrated in this report, the power limiting enforcement is effective and the total normalized time-averaged RF exposure does not exceed 1.0 for all the transmission scenarios. Therefore, the EUT complies with FCC RF exposure requirement.

8. Annex

8.1 Test sequence is generated based on below parameters of the DUT:

1. Measured maximum power (Pmax)
2. Measured Tx power (Plimit) to satisfy SAR Compliance
3. Setup time to make SAR Remaining be full
4. Do test according to test sequence

8.2 Test Sequence A waveform:

- Based on the parameters above, the Test Sequence A is generated with two power levels. One is maximum power level and the other is lower power level. The lower power level is defined as 3dB lower value than maximum power level. At first, maximum power level is applied for 80 seconds (SAR_time_window x 1.2). After then, lower power level is used until this test is finished.

8.3 Test Sequence B waveform:

- Based on the parameters above, the Test Type B is generated with pre-defined power levels, which is described in Table 10.3.1.

Table 10.3.1 Table of test sequence B

Time duration (second)	Power level (dB)
15	Plimit - 5
20	Plimit
20	Plimit + 5
10	Plimit – 6
20	Pmax
15	Plimit
15	Plimit -7
20	Pmax
10	Plimit-5
15	Plimit
10	Plimit-6
20	Plimit + 5
10	Plimit – 4
15	Plimit
10	Plimit – 6
20	Pmax
15	Plimit-8
15	Plimit
20	Pmax
10	Plimit – 9
20	Plimit + 5
20	Plimit
15	Plimit – 5

**9. Test Equipment List**

Manufacturer	Name of Equipment	Type/Model	Serial Number	Calibration	
				Last Cal.	Due Date
Anritsu	Base Station	MT8821	6201381768	Feb. 29, 2024	Feb. 28, 2025
Anritsu	Base Station	MT8000	6262208374	Feb. 29, 2024	Feb. 28, 2025
Testo	Hygro meter	608-H1	45196600	Nov. 02, 2023	Nov. 01, 2024
Anritsu	Signal Generator	MG3710A	6201502524	Sep. 27, 2023	Sep. 26, 2024
Anritsu	Power Meter	ML2496A	2119003	Jul. 16, 2024	Jul. 15, 2025
Anritsu	Power Sensor	MA2411B	1911333	Jul. 15, 2024	Jul. 14, 2025
Keysight	CATR measurement antenna	SAF-2434231535-328-S1-280-DP	16920-01	Note ⁽¹⁾	
Warison	10-50 GHz Directional Coupler	WCOU-10-50S-10	WR889BMC4B1	Note ⁽¹⁾	
ATM	500M-18GHz Dual Directional Coupler	C122H-10	P610410z-02	Note ⁽¹⁾	
Woken	Attenuator 1	WK0602-XX	N/A	Note ⁽¹⁾	
Woken	Attenuator 2	PE7005-10	N/A	Note ⁽¹⁾	
Woken	Attenuator 3	PE7005- 3	N/A	Note ⁽¹⁾	

Note ⁽¹⁾: Prior to conducted or EIRP power measurement, the path loss from the EUT to the power meter, which includes the RF cable, attenuator and directional coupler, was measured and determined.